

TMP1826 Single-Wire, $\pm 0.3^\circ\text{C}$ Accurate Temperature Sensor With 2-Kbit EEPROM

1 Features

- Single-wire interface with multi-drop shared bus and CRC
- Bus powered with operating voltage from 1.7 V to 5.5 V
- IEC 61000-4-2 ESD for 8-kV contact discharge
- High-accuracy digital temperature sensor:
 - $\pm 0.1^\circ\text{C}$ (typical)/ $\pm 0.3^\circ\text{C}$ (maximum) from -20°C to $+85^\circ\text{C}$
 - $\pm 0.3^\circ\text{C}$ (typical)/ $\pm 0.5^\circ\text{C}$ (maximum) from -40°C to $+125^\circ\text{C}$
- Active current of 100- μA (typical) and shutdown current of 0.37 μA (typical)
- 16-bit temperature resolution: 7.8 m°C (1 LSB)
- Fast data rates of 90 kbps in overdrive speed
- 2-Kbit EEPROM features:
 - Write in 64-bit blocks
 - Continuous read mode
 - Read with write protection in 256-bit blocks
 - Read/write current of 95 μA /178 μA (typical)
- NIST traceable factory-programmed non erasable 64-bit identification number for device addressing
- 4 configurable open-drain digital input-output

2 Applications

- Factory automation and control
- Appliances
- Medical accessories
- CPAP machine
- Battery packs
- Cold chain applications
- Temperature transmitters
- EV charging infrastructure

3 Description

The TMP1826 is a high-accuracy, single-wire compatible digital output temperature sensor with integrated 2-Kbit EEPROM. The TMP1826 provides a high accuracy of $\pm 0.1^\circ\text{C}$ (typical)/ $\pm 0.3^\circ\text{C}$ (maximum) across the temperature range of -20°C to $+85^\circ\text{C}$. Each device comes with a factory programmed 64-bit unique identification number for addressing and NIST traceability. The TMP1826 supports both standard speed for legacy application and over drive mode with 90-kbps data rate for low latency communication.

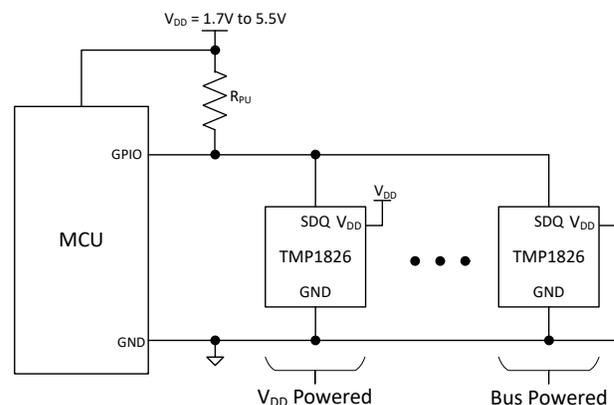
In the simplest mode of operation, the TMP1826 single-wire interface, with an integrated 8-kV IEC-61000-4-2 ESD protection on the data pin, requires only a single connection and a ground return in bus powered mode, which simplifies and reduces cost by reducing the number of wires and external protection components. Additionally, there is the V_{DD} power pin also available for applications that may want to have a dedicated power supply.

The 2-Kbit EEPROM on the TMP1826 allows the host to store application data in increments of 64 bits. With user programmable 256-bit page size write protection to avoid accidental overwrite, the EEPROM can be used as non-volatile, read-only memory. The four digital I/O pins are configurable for general purpose functions, temperature alert, or provide host to identify the position of the device on a shared bus.

Device Information

PART NUMBER	PACKAGE ⁽¹⁾	BODY SIZE (NOM)
TMP1826	VSSOP (8)	3.00 mm × 3.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Simplified Schematic



Table of Contents

1 Features	1	7.4 Device Functional Modes.....	18
2 Applications	1	7.5 Programming.....	32
3 Description	1	7.6 Register Maps.....	35
4 Revision History	2	8 Application and Implementation	44
5 Pin Configuration and Functions	3	8.1 Application Information.....	44
6 Specifications	3	8.2 Typical Applications.....	44
6.1 Absolute Maximum Ratings.....	3	9 Power Supply Recommendations	47
6.2 ESD Ratings.....	3	10 Layout	48
6.3 Recommended Operating Conditions.....	4	10.1 Layout Guidelines.....	48
6.4 Thermal Information.....	4	10.2 Layout Example.....	48
6.5 Electrical Characteristics.....	4	11 Device and Documentation Support	49
6.6 Single-Wire Interface Timing.....	5	11.1 Receiving Notification of Documentation Updates..	49
6.7 EEPROM Characteristics.....	6	11.2 Support Resources.....	49
6.8 Timing Diagrams.....	6	11.3 Trademarks.....	49
6.9 Typical Characteristics.....	9	11.4 Electrostatic Discharge Caution.....	49
7 Detailed Description	11	11.5 Glossary.....	49
7.1 Overview.....	11	12 Mechanical, Packaging, and Orderable Information	49
7.2 Functional Block Diagram.....	11		
7.3 Feature Description.....	11		

4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

DATE	REVISION	NOTES
February 2022	*	Initial release.

5 Pin Configuration and Functions

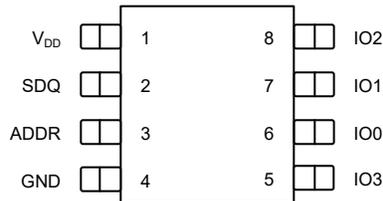


Figure 5-1. DGK 8-Pin VSSOP Top View

Table 5-1. Pin Functions

PIN		I/O	DESCRIPTION
NAME	VSSOP		
ADDR	3	I	Reserved for future use. If unused, must be connected to ground
GND	4	—	Ground
IO0	6	I/O	General purpose digital IO. If unused, must be connected to ground
IO1	7	I/O	General purpose digital IO. If unused, must be connected to ground
IO2	8	I/O	General purpose digital IO or configurable as temperature alert. If unused, must be connected to ground
IO3	5	I/O	General purpose digital IO. If unused, must be connected to ground
SDQ	2	I/O	Serial bidirectional data. In bus power mode, the pin is used to power the internal capacitor
V _{DD}	1	I	Supply voltage in V _{DD} powered mode. In bus powered mode, must be connected to ground

6 Specifications

6.1 Absolute Maximum Ratings

Over free-air temperature range unless otherwise noted⁽¹⁾

		MIN	MAX	UNIT
Supply voltage	V _{DD}		6.5	V
I/O voltage	SDQ, Bus powered mode	-0.3	6.5	V
	SDQ, Supply powered mode	-0.3	V _{DD} + 0.3	
I/O voltage	IO0, IO1, IO2, IO3	-0.3	6.5	V
Operating junction temperature, T _J		-55	155	°C
Storage temperature, T _{stg}		-65	155	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions*. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

6.2 ESD Ratings

			VALUE	UNIT	
V _(ESD)	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	All pins	±2000	V
		Charged-device model (CDM), per JEDEC specification per ANSI/ESDA/JEDEC JS-002 ⁽²⁾	All pins	±500	V
		IEC 61000-4-2 Contact Discharge	SDQ pin	±8000	V

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
 (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

		MIN	NOM	MAX	UNIT
V _{DD}	Supply voltage V _{DD} powered mode	1.70		5.5	V
V _{PUR}	Supply voltage bus powered mode ⁽¹⁾	1.70		5.5	V
V _{IO}	All IO pins except SDQ	0		5.5	V
V _{SDQ}	SDQ pin in V _{DD} powered mode	0		V _{DD} + 0.3	V
T _A	Operating ambient temperature	-40		125	°C

(1) Bus powered mode from 1.7 V to 3.3 V supported in overdrive speed only.

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾		TMP1826		UNIT
		DGK (VSSOP)		
		8-PINS		
R _{θJA}	Junction-to-ambient thermal resistance	158.2		°C/W
R _{θJC(top)}	Junction-to-case (top) thermal resistance	52.6		°C/W
R _{θJB}	Junction-to-board thermal resistance	79		°C/W
ψ _{JT}	Junction-to-top characterization parameter	4.9		°C/W
ψ _{JB}	Junction-to-board characterization parameter	77.5		°C/W
M _T	Thermal Mass	TBD		mJ/°C

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).

6.5 Electrical Characteristics

Over free-air temperature range and V_{DD} = 1.7 V to 5.5 V (unless otherwise noted); Typical specifications are at T_A = 25 °C and V_{DD} = 3.3 V (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
TEMPERATURE SENSOR							
T _{ERR}	Temperature accuracy	-20 °C to 85 °C			±0.1	±0.3	°C
		-40 °C to 125 °C			±0.3	±0.5	
PSR	DC power supply sensitivity					±0.03	°C/V
T _{RES}	Temperature resolution	Including sign bit			16		Bits
		LSB			7.8125		m°C
T _{REPEAT}	Repeatability ⁽¹⁾	V _{DD} = 3.3 V AVG_SEL = 1, CONV_TIME_SEL = 1 1-Hz conversion interval, 300 acquisition			2		LSB
T _{LTD}	Long-term stability and drift	1000 hours at 125°C ⁽²⁾			TBD		°C
t _{RESP_L}	Reponse time (Stirred Liquid)	Single layer Flex PCB	τ = 63 % 25 °C to 75 °C		TBD		ms
		2-layer 62-mil Rigid PCB			TBD		ms
T _{HYST}	Temperature cycling and hysteresis	T _{START} = -40 °C T _{FINISH} = 125 °C T _{TEST} = 25 °C 3 cycles			4		LSB
t _{ACT}	Active Conversion time (No Averaging)	(Figure 7-8)			5.7		ms
t _{DELAY}	Command start-up delay for temperature conversion and EEPROM programming			100		300	µs
SDQ DIGITAL INPUT/OUTPUT							
C _{SDQ}	SDQ pin capacitance				40		pF
V _{IL}	Input logic low level ⁽³⁾			-0.3		0.2 × V _S	V
V _{IH}	Input logic high level ⁽³⁾			0.8 × V _S		V _S + 0.3	V

Over free-air temperature range and $V_{DD} = 1.7\text{ V}$ to 5.5 V (unless otherwise noted); Typical specifications are at $T_A = 25\text{ }^\circ\text{C}$ and $V_{DD} = 3.3\text{ V}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{HYST}	Hysteresis			0.3		V
I_{IN}	Input leakage current			± 0.5	TBD	μA
V_{OL}	Output low level	$I_{OL} = -4\text{ mA}$			0.4	V
GPIO CHARACTERISTICS						
C_{IN}	Input capacitance			10		pF
V_{IL}	Input logic low level ⁽³⁾		-0.3	$0.2 \times V_S$		V
V_{IH}	Input logic high level ⁽³⁾		$0.8 \times V_S$		V_S	V
I_{IN}	Input leakage current			0	TBD	μA
V_{HYST}	Hysteresis			0.175		V
V_{OL}	Output low level	$I_{OL} = -4\text{ mA}$			0.4	V
POWER SUPPLY						
I_{PU}	Pullup current ⁽⁴⁾	Bus powered mode, serial bus inactive	300			μA
I_{DD_ACTIVE}	Supply current during active conversion	Active Conversion, serial bus inactive		100	TBD	μA
I_{DD_SB}	Standby current ⁽⁵⁾	V_{DD} powered, serial bus inactive, continuous conversion mode	$T_A = -40\text{ }^\circ\text{C}$ to $85\text{ }^\circ\text{C}$	12.5	TBD	μA
			$T_A = -40\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$		TBD	
I_{DD_SD}	Shutdown current	Bus powered, serial bus inactive, one shot conversion mode	$T_A = -40\text{ }^\circ\text{C}$ to $85\text{ }^\circ\text{C}$	0.37	TBD	μA
			$T_A = -40\text{ }^\circ\text{C}$ to $125\text{ }^\circ\text{C}$		TBD	
V_{POR}	Power-on reset threshold voltage	Supply rising (Figure 6-4, Figure 6-5)		1.25		V
	Brownout detect	Supply falling		1.15		V
t_{INIT}	Power on Reset Initialization Time	Time required by device to reset after power up (Figure 6-4, Figure 6-5)			2.0	ms

- Repeatability is the ability to reproduce a reading when the measured temperature is applied consecutively, under the same conditions.
- Long term stability is determined using accelerated operational life testing at a junction temperature of $125\text{ }^\circ\text{C}$.
- In bus powered mode $V_S = V_{PUR}$. In supply powered mode, $V_S = V_{DD}$
- The pullup current parameter is required to size the bus pullup resistor for active temperature conversion or EEPROM read, erase and program operations.
- Quiescent current between conversions.

6.6 Single-Wire Interface Timing

Over free-air temperature range and $V_{DD} = 1.70\text{ V}$ to 5.5 V (unless otherwise noted)

		STANDARD MODE		OVERDRIVE MODE		UNIT
		MIN	MAX	MIN	MAX	
BUS RESET AND BIT SLOT TIMING						
t_{RSTL}	Host to device bus reset pulse width (Figure 6-1) ⁽¹⁾	480	560	48	80	μs
t_{RSTH}	Device to host response time (Figure 6-1) ⁽²⁾	480		48		μs
t_{PDH}	Device turnaround time for bus reset response (Figure 6-1)	15	60	2	8	μs
t_{PDL}	Device to host response pulse width (Figure 6-1)	60	240	8	24	μs
t_{SLOT}	Bit slot time (Figure 6-2, Figure 6-3)	60	120	11		μs
t_{REC}	Recovery time (Figure 6-2, Figure 6-3)	2		2		μs
t_{GF}	Glitch filter width (Figure 6-6) ⁽³⁾	0.48		0.025		μs
t_F	Fall time		100		100	ns
BIT WRITE TIMING						
t_{WR0L}	Host write 0 width (Figure 6-2)	60	120	9	10	μs

Over free-air temperature range and $V_{DD} = 1.70\text{ V}$ to 5.5 V (unless otherwise noted)

		STANDARD MODE		OVERDRIVE MODE		UNIT
		MIN	MAX	MIN	MAX	
t_{WR1L}	Host write 1 width (Figure 6-2)	2	15	1	2	μs
t_{RDV}	Device read data valid time (Figure 6-2)	15		2		μs
t_{DSW}	Device read data window (Figure 6-2)	15	45	2	7	μs
BIT READ TIMING						
t_{RL}	Host drive read bit slot time (Figure 6-3)	2	5	1	2	μs
t_{RWAIT}	Host wait time before read data sampling window (Figure 6-3) ⁽⁴⁾		$t_{RL}+t_{RC}$		$t_{RL}+t_{RC}$	μs
t_{MSW}	Host read data sampling window (Figure 6-3)	$t_{RL}+t_{RC}$	30	$t_{RL}+t_{RC}$	3	μs

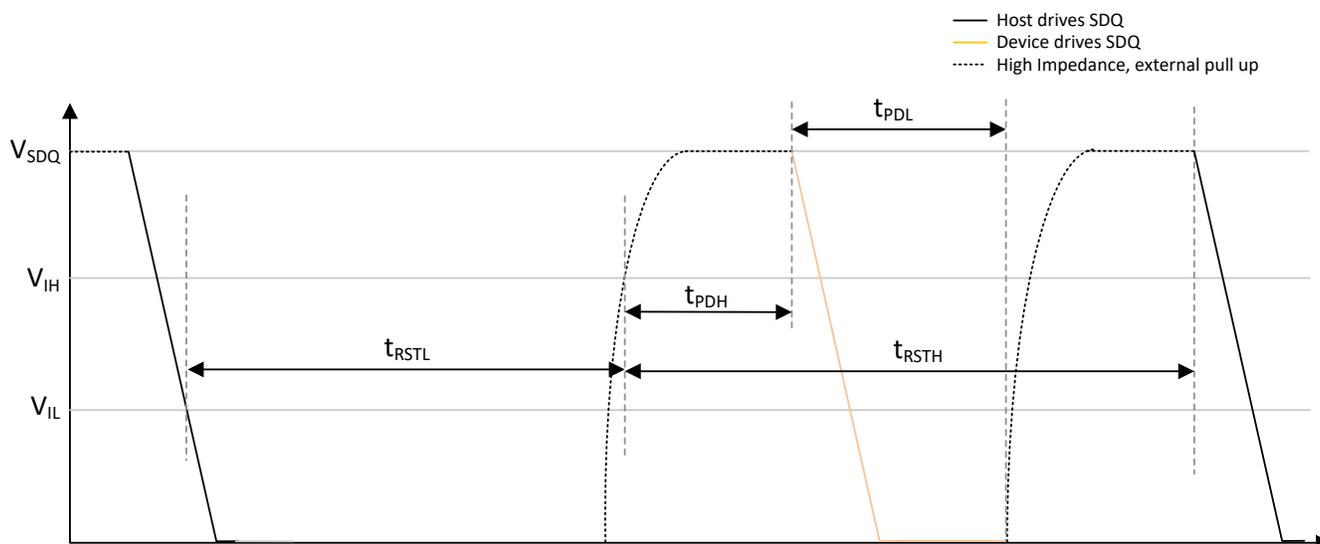
- (1) In bus powered mode, extending the t_{RSTL} above $600\ \mu\text{s}$ may cause the device to power on reset
- (2) The t_{RSTH} is the maximum time the host must wait to receive a response from the furthest device, taking into account the propagation delay and recovery time for all the devices.
- (3) The glitch filter timing applies only on the rising edge of the SDQ signal
- (4) The t_{RC} time is defined as the time taken for the bus voltage to rise from 0V to minimum V_{IH} of the host. This is a function of the bus pull up resistor and parasitic capacitance of the trace or cable.

6.7 EEPROM Characteristics

 Over free-air temperature range and $V_{DD} = 1.7\text{ V}$ to 5.5 V (unless otherwise noted); Typical specifications are at $T_A = 25^\circ\text{C}$ and $V_{DD} = 3.3\text{ V}$ (unless otherwise noted)

		MIN	TYP	MAX	UNIT
t_{PROG}	Programming time for 8-byte block		13.2	21	ms
$t_{READIDLE}$	Idle bus time for EEPROM 8-byte block read			400	μs
I_{DD_PROG}	Programming current		178	TBD	μA
Data Retention	at $T_A = 125^\circ\text{C}$	25			years
Endurance		1000	20000		cycles

6.8 Timing Diagrams


Figure 6-1. Bus Reset Timing Diagram

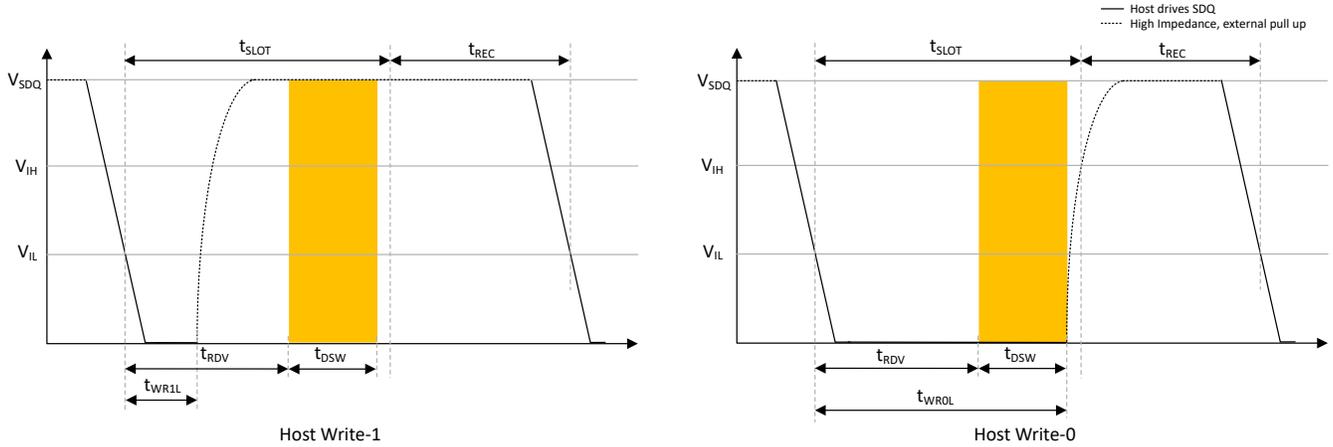


Figure 6-2. Write Timing Diagram

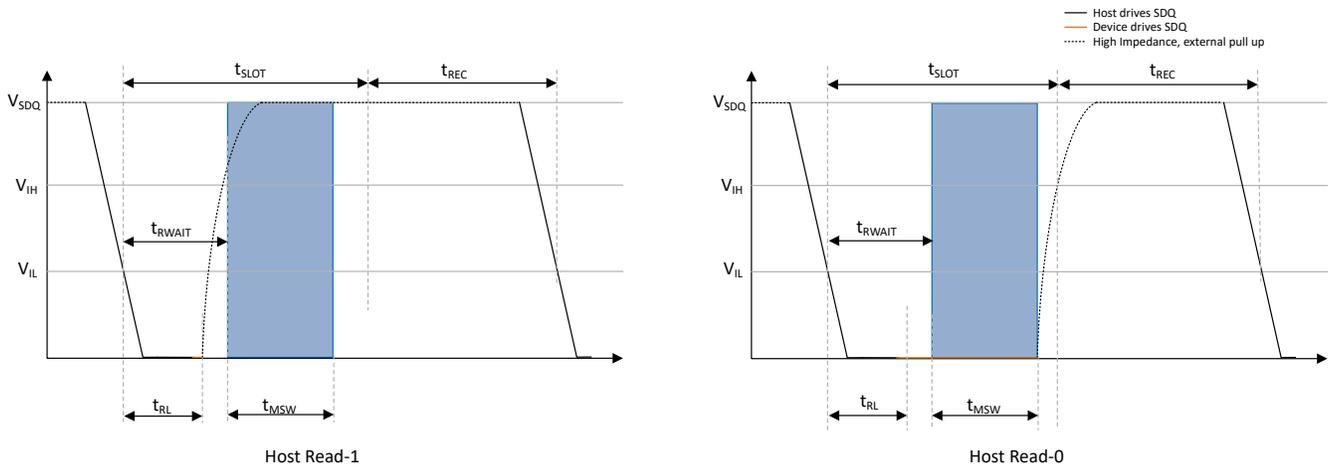


Figure 6-3. Read Timing Diagram

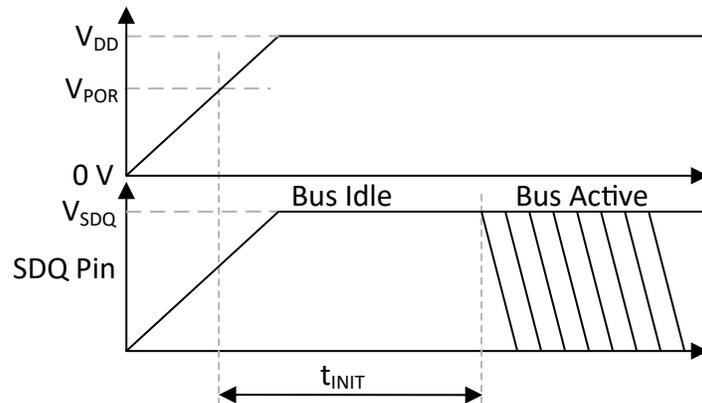


Figure 6-4. V_{DD} Powered Initialization Timing Diagram

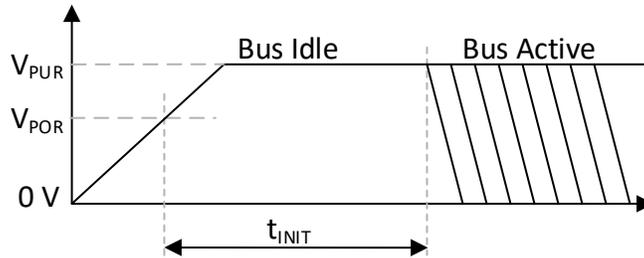


Figure 6-5. Bus Powered Initialization Timing Diagram

ADVANCE INFORMATION

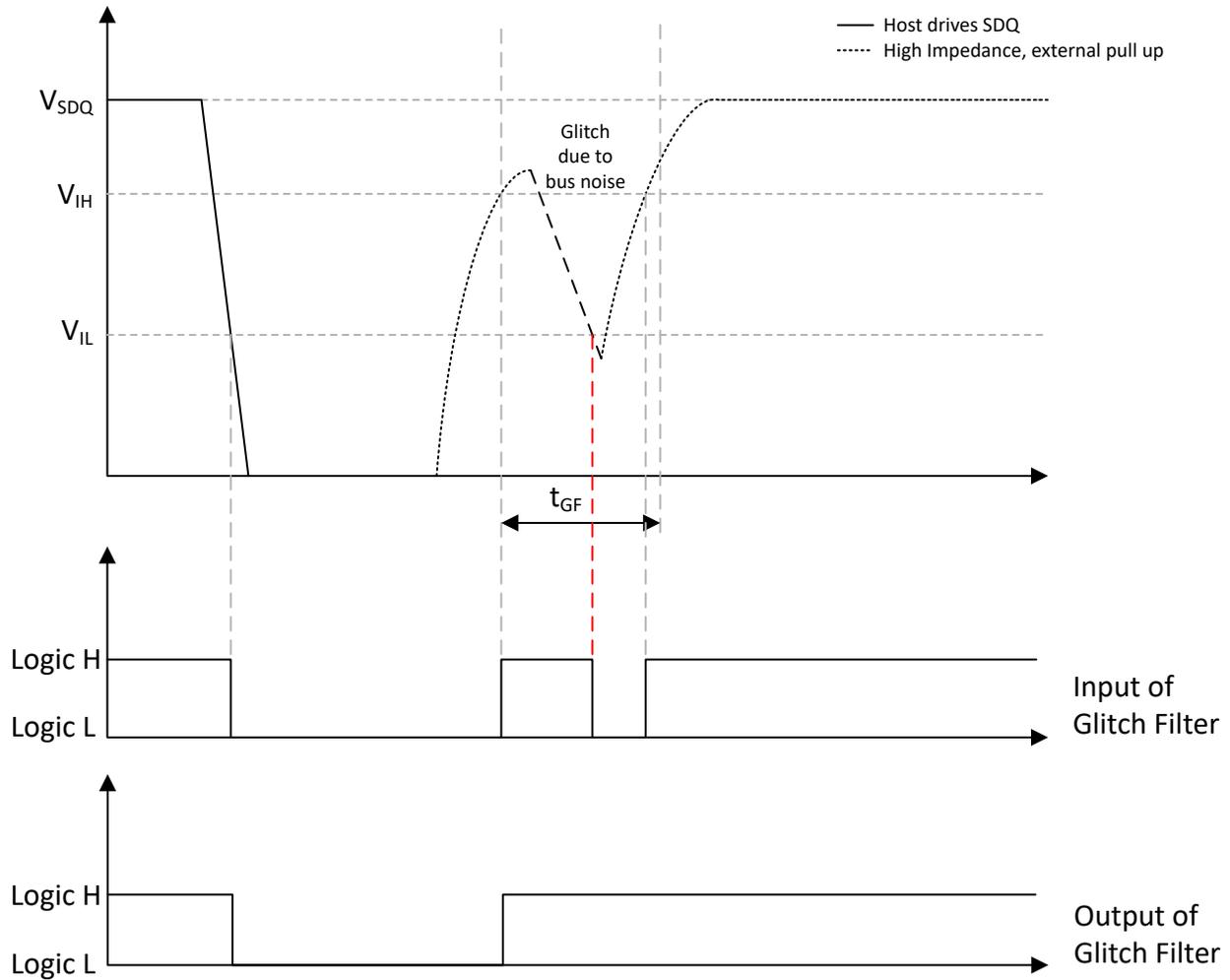


Figure 6-6. Glitch Filter Timing Diagram

6.9 Typical Characteristics

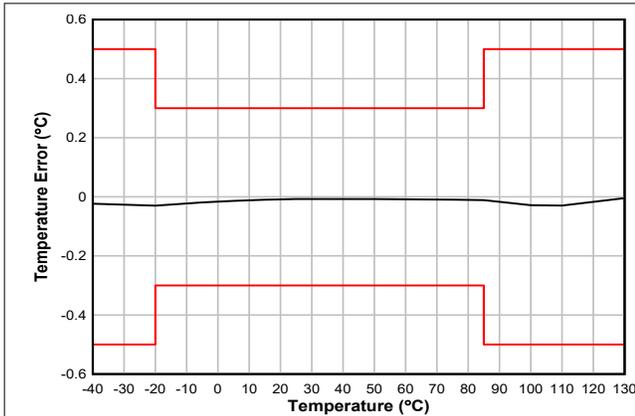


Figure 6-7. Temperature Error vs. Temperature

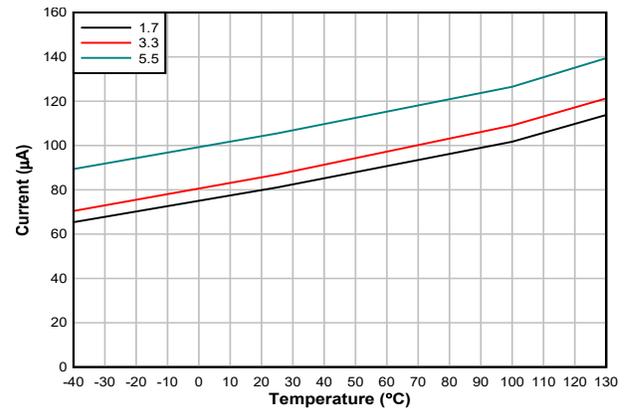


Figure 6-8. Active Current vs. Temperature

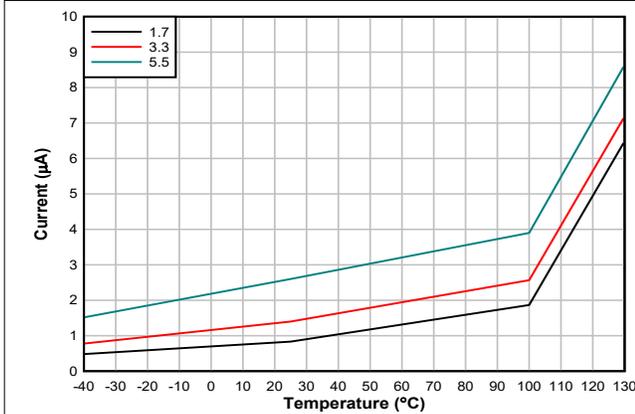
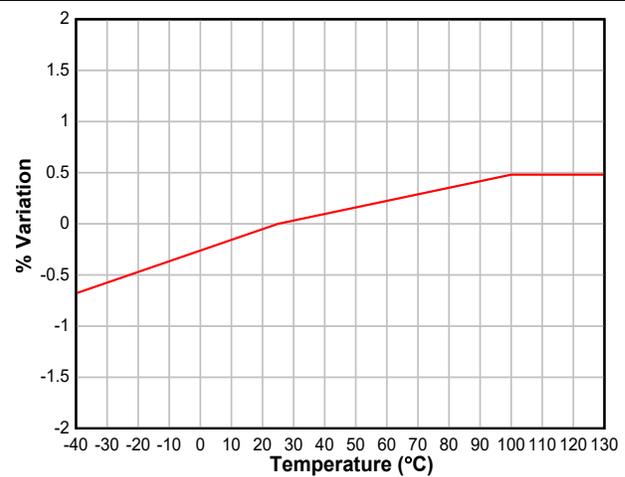
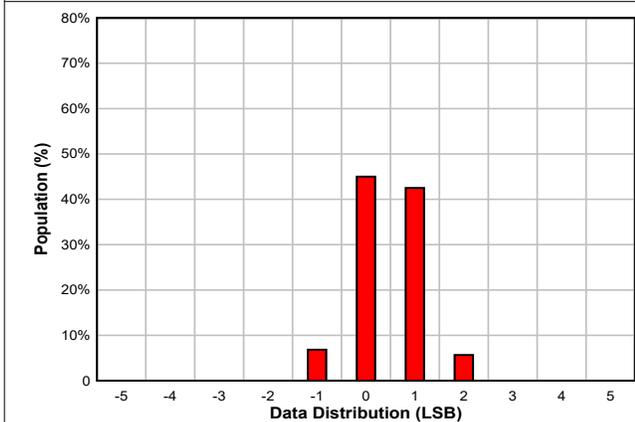


Figure 6-9. Shutdown Current vs. Temperature



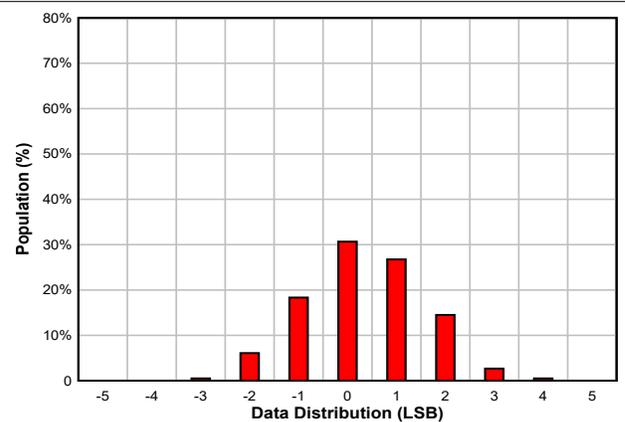
$V_{DD} = 1.7\text{ V to }5.5\text{ V}$

Figure 6-10. Conversion Time vs. Temperature



$T_A = 25\text{ }^\circ\text{C}$

Figure 6-11. Data Distribution With 5.5-ms Conversion Time and Averaging On

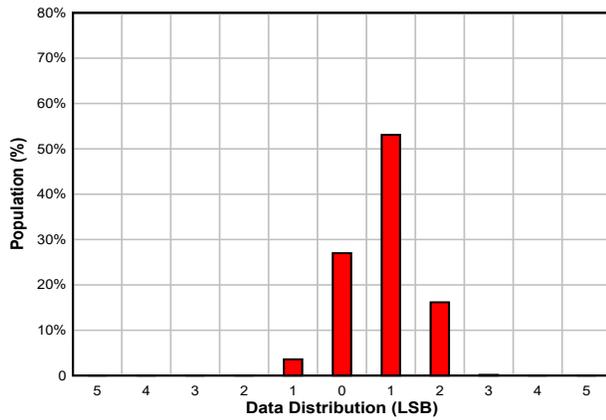


$T_A = 25\text{ }^\circ\text{C}$

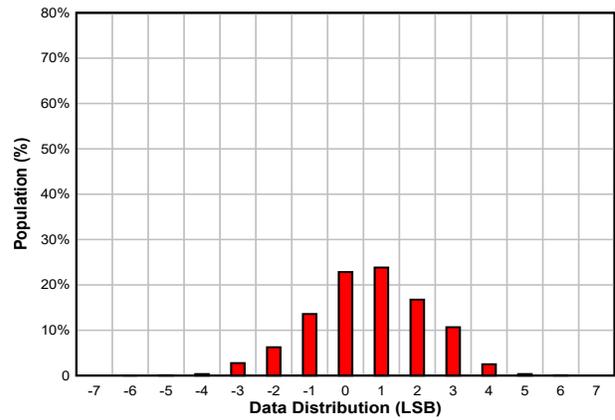
Figure 6-12. Data Distribution With 5.5-ms Conversion Time and Averaging Off

6.9 Typical Characteristics (continued)

ADVANCE INFORMATION



$T_A = 25\text{ }^\circ\text{C}$
Figure 6-13. Data Distribution With 3-ms Conversion Time and Averaging On



$T_A = 25\text{ }^\circ\text{C}$
Figure 6-14. Data Distribution With 3-ms Conversion Time and Averaging Off

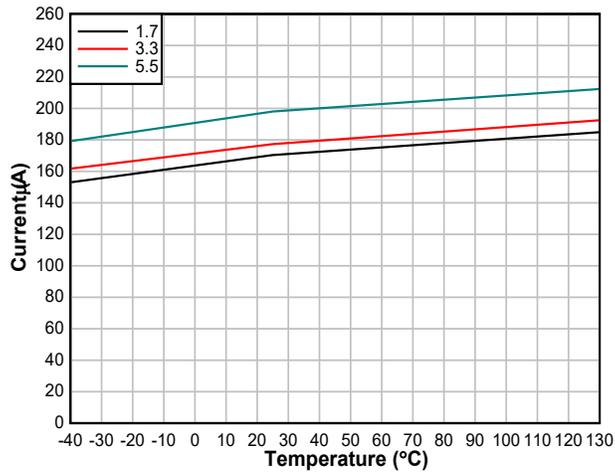


Figure 6-15. EEPROM Programming Current vs. Temperature

7 Detailed Description

7.1 Overview

The TMP1826 is a digital output temperature sensor designed for thermal-management and thermal-protection applications. The TMP1826 is a single-wire device which can operate in either supply powered or bus powered (parasitic powered) mode. The device features a 2-Kbit EEPROM. Figure 7-1 shows a block diagram of the TMP1826.

7.2 Functional Block Diagram

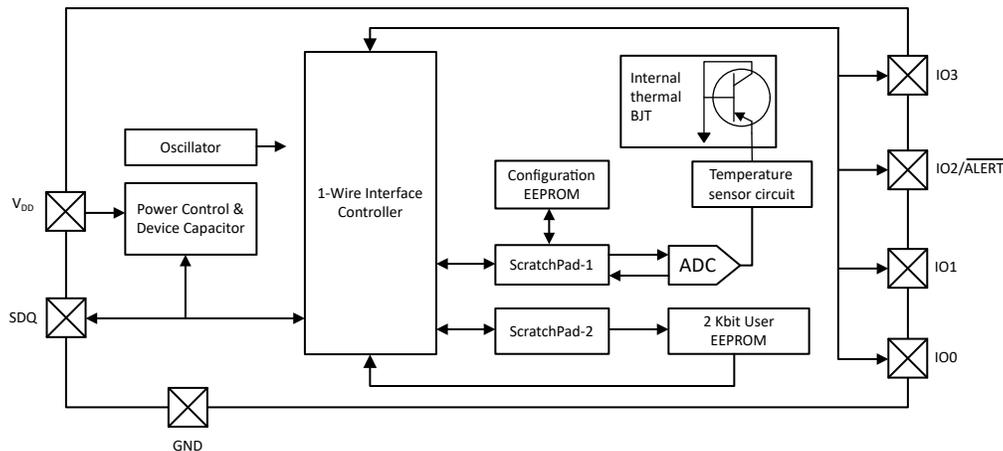


Figure 7-1. Functional Block Diagram

7.3 Feature Description

7.3.1 Power Up

The device operates in both supply powered and bus powered mode. Irrespective of the mode, when the supply voltage reaches within the operating range, the device requires t_{INIT} to initialize itself. After t_{INIT} , the host MCU can begin accessing the device.

During initialization, the device may not respond to any bus activity. When initialization is complete, the device shall wait for the bus reset from the host. During the initialization for the device, the following events take place:

- The EEPROM content for STACKMODE_ADDR, TEMP_ALERT_LOW, TEMP_ALERT_HIGH and TEMP_OFFSET are restored to the respective registers.
- The EEPROM for the IO configuration register is read and contents of the IO_CONFIG register is restored.
- The EEPROM content for DEVICE_CONFIG1, DEVICE_CONFIG2 are restored to the respective registers.
 - If the ARB_MODE bits are set to value other than '00', then the device will respond to the SEARCHADDR in arbitration mode.
 - If OD_EN bit is set to '1', then the device shall communicate in overdrive speed, unless the first bus reset pulse from the host is sent in standard speed.
- The user memory protection bits are restored and appropriate protection to the user EEPROM block applied.

7.3.2 Power Mode Switch

The device is designed to operate in supply powered or bus powered mode. The dual mode implementation provides a unique method of redundancy that, even in cases where the power supply pin gets disconnected, the device can draw power from data pin, as long as the pullup resistor value used is as per the specification limit. This may be the system case where while operating in supply powered mode, the supply pin may accidentally get disconnected, especially under harsh operating conditions.

When the device switches from supply powered to bus powered mode, the device shall operate with the same settings until the internal capacitor is able to provide the current draw required by the device for communication and the external pullup resistor can charge the internal capacitor during bus idle time. If the internal voltage on the capacitor drops below the brown-out threshold, the device shall switch itself off and enter bus powered mode

of communication on subsequent power up. The device may not complete the ongoing communication during this time. When the device completes the power-up initialization sequence, as described earlier, the device shall respond to first bus communication starting with the bus reset sequence.

7.3.3 Bus Pullup Resistor

The bus pullup resistance value selected, is important for communication as per the speed mode and ensuring that minimal possible energy is consumed in the application. If the resistor value is too small, it may violate the V_{OL} limits on the SDQ pin.

The total SDQ pin and bus capacitance must be considered along with the bus leakage current when selecting the pullup resistor. The pullup resistance value selected must also ensure that the signal level reaches V_{IH} as per the timing requirements for standard and overdrive mode.

In bus powered mode of operation, the device charges its internal capacitor through the SDQ pin and the pullup resistor. This charge on the capacitor is used during bus communication, when the SDQ pin low. For other high current functions like thermal conversion and EEPROM access, the bus is held idle to ensure that the device can draw current through the pullup resistor. The SDQ pin voltage during the high current operation must be maintained to ensure sufficient operating margins. Use [Equation 1](#) to calculate the pullup resistor value.

$$R_{PUR} < (V_{PUR} - 1.6 \text{ V}) \div I_{PU(MIN)} \quad (1)$$

When the device is used in V_{DD} or supply powered mode, a larger pullup resistor value may be used, as the SDQ pin is used only for communication. The user must ensure that the pullup resistor value selected must be able to support the timing for the required bus speed of operation.

For low current consumption devices like TMP1826, selecting the correct pullup resistor value allows the application to avoid low impedance current path components for bus powered mode of operation while maintaining communication speeds and device parameters as per its electrical specification.

7.3.4 Temperature Results

The conversion is initiated by the host MCU by sending the temperature conversion command if the automatic conversion is disabled, or immediately after the presence detect is completed when the automatic conversion is enabled, or in continuous conversion mode if the device is V_{DD} powered. At the end of every conversion, the device updates the temperature registers [TEMP_RESULT_L](#), [TEMP_RESULT_H](#) and the [STATUS](#) register bits. As shown in [Figure 7-2](#), the device supports a high precision and legacy format, which can be configured through the [TEMP_FMT](#) bit in the [device configuration-1](#) register.

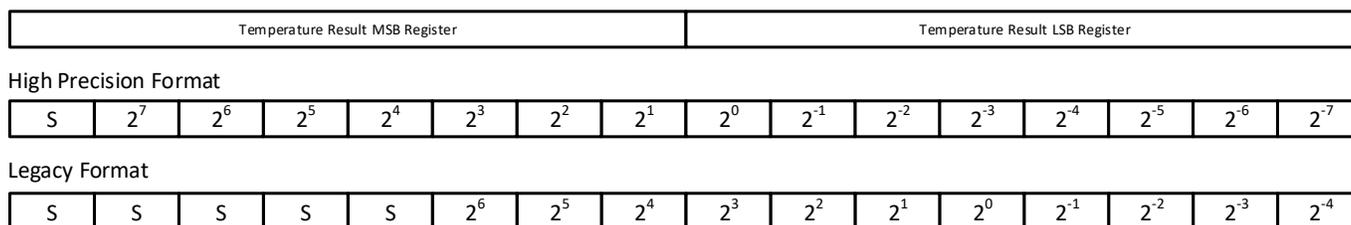


Figure 7-2. Temperature Format

If the format selected is the high precision 16-bit format, the data in the result registers is stored in two's complement form and has a resolution of 0.0078125°C. If the format selected is the legacy 12-bit format, the data in the result register is stored in sign extended form and has a resolution of 0.0625°C. The temperature register reads as 25°C in 16-bit mode before the first conversion. [Table 7-1](#) shows examples of possible binary data that can be read from the temperature result registers and the corresponding hexadecimal and temperature equivalents for both formats.

Table 7-1. Temperature Data Format

TEMPERATURE (°C)	DIGITAL OUTPUT (PRECISION FORMAT)		DIGITAL OUTPUT (LEGACY FORMAT)	
	BINARY	HEXADECIMAL	BINARY	HEXADECIMAL
150	0100 1011 0000 0000	4B00	0000 0111 1111 1111	07FF

Table 7-1. Temperature Data Format (continued)

TEMPERATURE (°C)	DIGITAL OUTPUT (PRECISION FORMAT)		DIGITAL OUTPUT (LEGACY FORMAT)	
	BINARY	HEXADECIMAL	BINARY	HEXADECIMAL
127	0011 1111 1000 0000	3F80	0000 0111 1111 0000	07F0
100	0011 0010 0000 0000	3200	0000 0110 0100 0000	0640
25	0000 1100 1000 0000	0C80	0000 0001 1001 0000	0190
1	0000 0000 1000 0000	0080	0000 0000 0001 0000	0010
0.125	0000 0000 0001 0000	0010	0000 0000 0000 0010	0002
0.03125	0000 0000 0000 0100	0004	0000 0000 0000 0000	0000
0.0078125	0000 0000 0000 0001	0001	0000 0000 0000 0000	0000
0	0000 0000 0000 0000	0000	0000 0000 0000 0000	0000
-0.0078125	1111 1111 1111 1111	FFFF	0000 0000 0000 0000	0000
-0.03125	1111 1111 1111 1100	FFFC	0000 0000 0000 0000	0000
-0.125	1111 1111 1111 0000	FFF0	1111 1111 1111 1110	FFFE
-1	1111 1111 1000 0000	FF80	1111 1111 1111 0000	FFF0
-25	1111 0011 1000 0000	F380	1111 1110 0111 0000	FE70
-40	1110 1100 0000 0000	FC00	1111 1101 1000 0000	FD80
-55	1110 0100 1000 0000	F480	1111 1100 1001 0000	FC90

7.3.5 Temperature Offset

The temperature offset has the same format as the temperature result and is stored in the [TEMP_OFFSET_L](#) and [TEMP_OFFSET_H](#) registers.

The device, after every temperature conversion, shall apply the offset value, before the temperature is stored in the temperature result register. The host write to the registers can be stored in the device's configuration EEPROM, thereby reducing the overhead as the host does not need to reprogram the values at every power up. The offset features allow the device to achieve better accuracy at the temperature range for the application by performing a single point calibration.

7.3.6 Temperature Alert

The temperature alert feature uses the [temperature alert low](#) registers for low threshold comparison and [temperature alert high](#) registers for high threshold comparison. The format of the register is the same as the temperature results.

The device shall compare the result of the last conversion with the alert thresholds. If the temperature result is less than the low limit, or more than the high limits, then the device shall set the appropriate alert status flag for low or high temperature limits, in the [status](#) register. The alert status flags are cleared based on the ALERT_MODE setting in the [device configuration-1](#) register.

Additionally, if the IO2 pin is configured as an alert pin, the alert status is reflected on the pin.

7.3.7 Standard Device Address

Every device comes with a unique 64-bit address that is factory programmed. This is described below.

7.3.7.1 Unique 64-Bit Device Address and ID

The device has a hard-coded, 64-bit address which is factory programmed and cannot be altered by the customer application. The unique 64-bit device address is used for device addressing in the end application and for NIST traceability. [Figure 7-3](#) shows the format of the 64-bit address. When the host accesses the device or when the device sends its address, the 64-bit unique address is sent least significant bit first. The unique 64-bit address consists of 3 fields. The lower 8 bits consists of the device family code, followed by a 48-bit unique number and 8-bit CRC checksum on the 56 bits preceding it.

The device family code for TMP1826 shall read as 43h.



Figure 7-3. 64-Bit Device Address

7.3.8 CRC Generation

The TMP1826 implements a cyclic redundancy check (CRC) mechanism for data integrity check and communication robustness. [Table 7-2](#) lists the properties of a 8-bit CRC.

Table 7-2. CRC-8 Rule

CRC-8 Rule	Attributes
CRC width	8 bits
CRC polynomial	$x^8 + x^5 + x^4 + 1$
Initial seed value	00h
Input data reflected	Yes
Output data reflected	Yes
XOR value	00h

When a new transaction is done, the shift register is initialized with the seed value of 00h and the data is shifted in LSB first. The CRC result is always part of the 64-bit unique address and is computed on the 56-bits that precede it. Additionally, when the host writes to the scratchpad-1 for the registers and scratchpad-2 for the memory, the device sends the CRC computed on the data bytes to provide a data integrity check for the host on the transaction. When the host reads the scratchpad-1 for reading the temperature register, the device shall append the CRC after the 8 bytes of scratchpad are sent.

The host must recalculate the CRC and compare it against the received CRC from the device. This is done by shifting the read data from the device along with CRC bits. If there is no bus error, then the shift register at the end of the bit shift will result in 00h. When writing the data to the device, the host must check the CRC received by processing the write data to ensure that there were no transmission errors and take appropriate corrective action before performing the next function.

7.3.9 Functional Register Map

The scratchpad-1 region and the IO register region together are referred to as the functional register map (see [Figure 7-4](#)). The scratchpad-1 region is 16 bytes deep, and consists of temperature result, device status, device configuration, stackmode address, temperature alert limit and temperature offset registers. The IO register region consists of the IO read and IO configuration registers. Some of the registers can be committed to the configuration EEPROM to ensure that the device setting are restored on power up without the host rewriting the configuration.

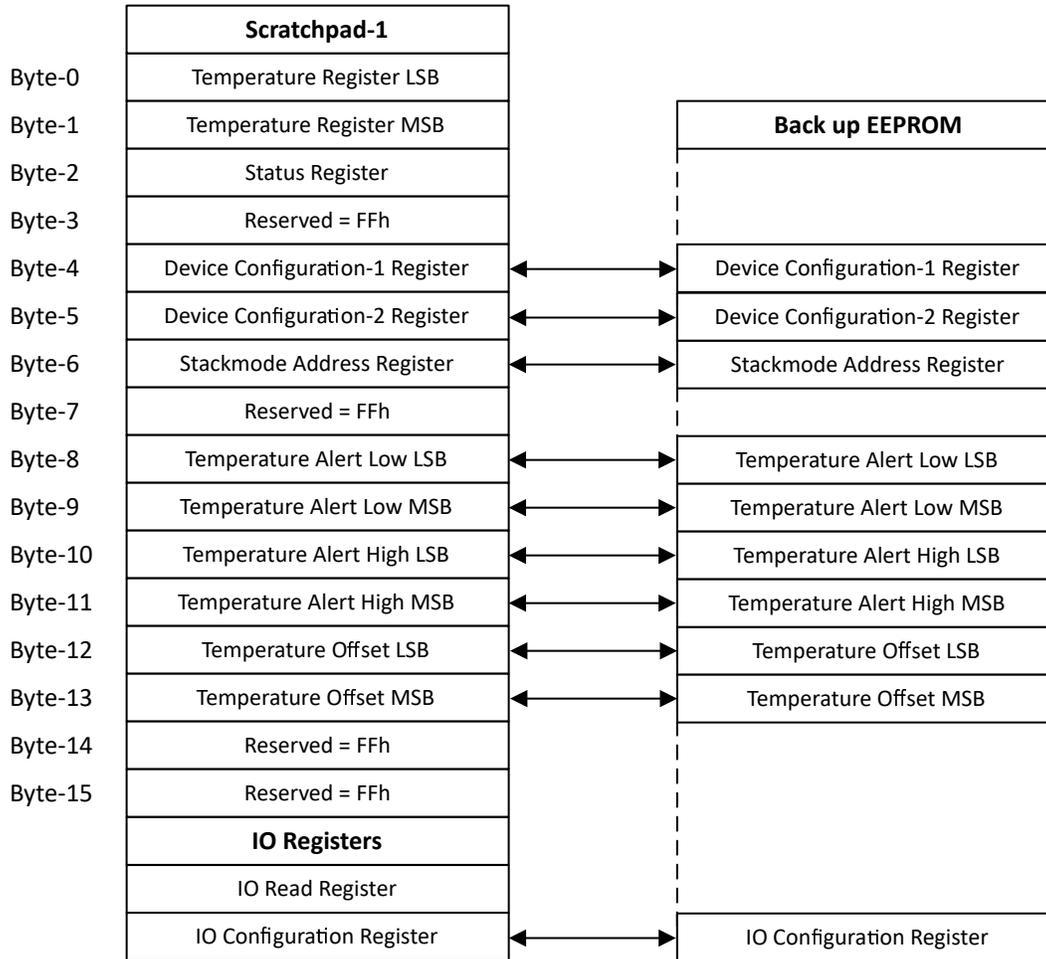


Figure 7-4. Functional Register Map (Scratchpad-1)

7.3.10 User Memory Map

The EEPROM memory is organized as 8 pages of 4 blocks each. Figure 7-5 shows that each block is 8 bytes or 64 bits. This results in a total user memory of 2048 bits. All memory access to the device shall be increments of a block size of 8 bytes. Access to the memory for programming is done through the scratchpad-2 register. The host writes to the scratchpad-2 register, which allows the device to perform a read before committing the content to the memory.

256 bytes	00FFh	Page 7	Block 3	00F8h – 00FFh
	00E0h		Block 2	00F0h – 00F7h
			Block 1	00E8h – 00EFh
			Block 0	00E0h – 00E7h
	00DFh	Page 6	Block 3	00D8h – 00DFh
	00C0h		Block 2	00D0h – 00D7h
			Block 1	00C8h – 00CFh
			Block 0	00C0h – 00C7h
	00BFh	Page 5	Block 3	00B8h – 00BFh
	00A0h		Block 2	00B0h – 00B7h
			Block 1	00A8h – 00AFh
			Block 0	00A0h – 00A7h
	009Fh	Page 4	Block 3	0098h – 009Fh
	0080h		Block 2	0090h – 0097h
			Block 1	0088h – 008Fh
			Block 0	0080h – 0087h
007Fh	Page 3	Block 3	0078h – 007Fh	
0060h		Block 2	0070h – 0077h	
		Block 1	0068h – 006Fh	
		Block 0	0060h – 0067h	
005Fh	Page 2	Block 3	0058h – 005Fh	
0040h		Block 2	0050h – 0057h	
		Block 1	0048h – 004Fh	
		Block 0	0040h – 0047h	
003Fh	Page 1	Block 3	0038h – 003Fh	
0020h		Block 2	0030h – 0037h	
		Block 1	0028h – 002Fh	
		Block 0	0020h – 0027h	
001Fh	Page 0	Block 3	0018h – 001Fh	
0000h		Block 2	0010h – 0017h	
		Block 1	0008h – 000Fh	
		Block 0	0000h – 0007h	

Figure 7-5. Address to EEPROM Page and Block Map

Note

The device shall return "1" for any device read without a CRC if the address is outside the user memory map.

7.3.11 Bit Communication

The single-wire interface communication does not have a reference clock, therefore all communication is performed asynchronously with fixed time slot (t_{SLOT}) and variable pulse width to indicate logic '0' and '1'. In idle state, the external pullup resistor holds the line high. All bit communication, whether it is a write or a read, are initiated by the host by driving the data line low to generate a falling edge and the bit value is decoded as the time for which the data line is held low or high after the falling edge.

Even though the communication is one bit at a time, the data exchanged between the host and device is performed at byte boundary. Every byte is sent least significant bit first. The device behavior is not ensured when incomplete bytes are sent.

7.3.11.1 Host Write/Device Read

A host write is the means by which the host sends the command, function and data to the device(s). A host write starts by the host driving the data line low as shown in Figure 7-6. If the host intends to transmit a logic '1', it releases the line after t_{WR1L} time. If the host intends to transmit a logic '0', it releases the line after t_{WR0L} . After releasing the data, the pullup resistor causes the line to become high till the beginning of the next time slot. The device samples the line after t_{RDV} has elapsed from the falling edge, for a time frame indicated by t_{DSW} . The host must factor the rise time due to the pullup resistor and bus capacitance to determine the release of the data line before the line is sampled by the device and the host drives the next write bit time slot.

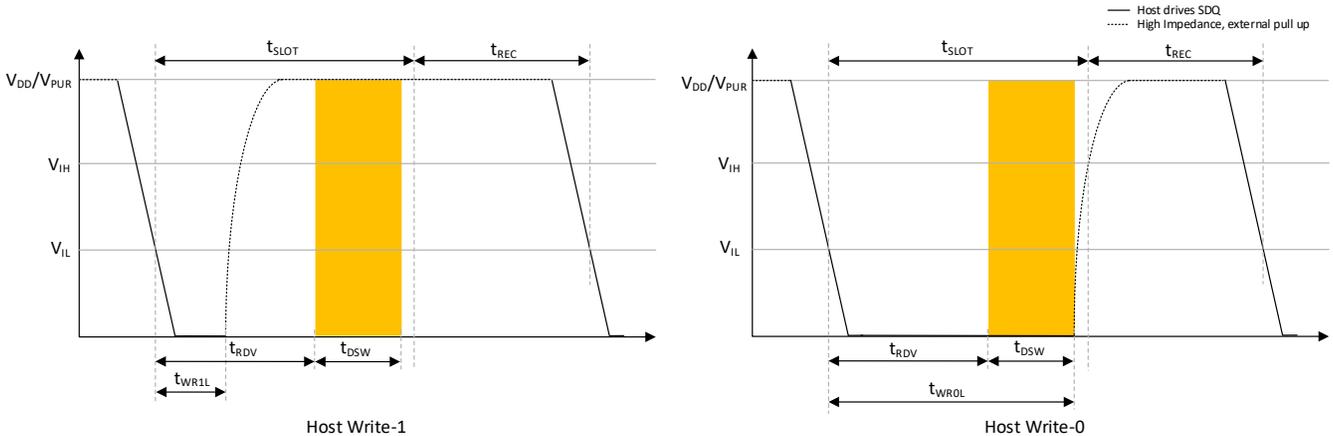


Figure 7-6. Host Write/Device Read

7.3.11.2 Host Read/Device Write

A host read is the means by which the hosts gets the data from the device or the CRC for data integrity check. A host read starts by the host driving the data line low as shown in Figure 7-7. When the device detects the falling edge, the device may drive the line low before the time t_{RL} . The host may release the bus from its side after the time $t_{RL(MIN)}$ elapses. If the device intends to transmit a logic '1', then it shall release the bus before $t_{RL(MAX)}$ elapses. If the device intends to transmit a logic '0', then it releases the bus after $t_{SLOT(MIN)}$. The host must sample the line after the time t_{RWAIT} , for a time frame indicated by t_{MSW} . The host must factor the rise time due to the pullup resistor and bus capacitance to determine the sampling window for the host to sample the bit level sent by the device or to drive the next read bit time slot.

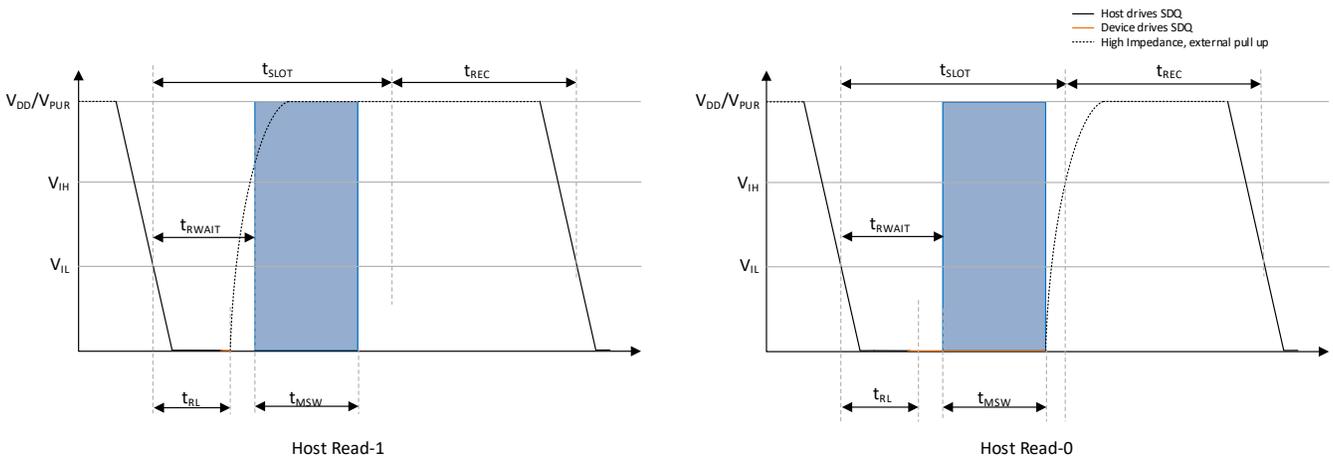


Figure 7-7. Host Read/Device Write

7.3.12 NIST Traceability

The accuracy of temperature testing is verified with equipment that is calibrated by an accredited lab that complies with ISO/IEC 17025 policies and procedures. Each device is tested and trimmed to conform to its respective data sheet specification limits.

7.4 Device Functional Modes

The TMP1826 device features flexible temperature conversion modes along with robust user EEPROM architecture, which is described in the sections below.

7.4.1 Conversion Modes

The TMP1826 supports both one-shot and continuous conversion modes. There are different methods for one-shot conversion modes, that may be used based on single device or multiple device bus network. The continuous conversion mode is only supported in V_{DD} powered mode. Each of the conversion modes are with single temperature sample, but the host can enable 8 samples averages in the device for improved accuracy.

7.4.1.1 Basic One-Shot Conversion Mode

The basic one-shot conversion mode is the default conversion mode. The device goes through a bus reset, address and function phase to initiate the temperature conversion. During the communication, the device is in shutdown mode. When the conversion request is registered by the device, the device starts active conversion and then goes back to low power shutdown mode as shown in Figure 7-8. If the device is in continuous conversion mode, then the one-shot conversion mode request is ignored.

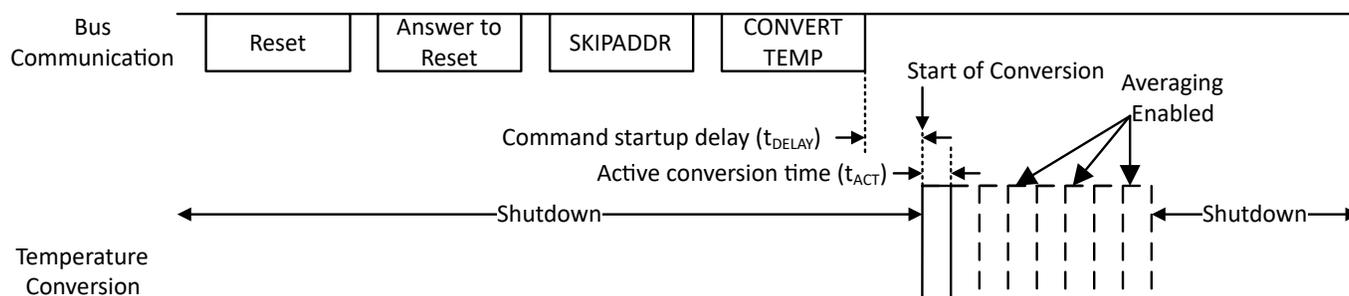


Figure 7-8. One-Shot Conversion Mode

As shown in Figure 7-9, there is no change in how one-shot conversion is performed when there are multiple devices on the bus. However, as there are multiple devices, the combined current drain in bus powered mode of operation may cause the bus voltage to drop. In such use cases, it is required that the host implement a low impedance current path using a FET/transistor switch. This path is switched on so as to meet the current

requirement of the bus during an active conversion and after the active conversion duration is complete, it is switched off for bus communication.

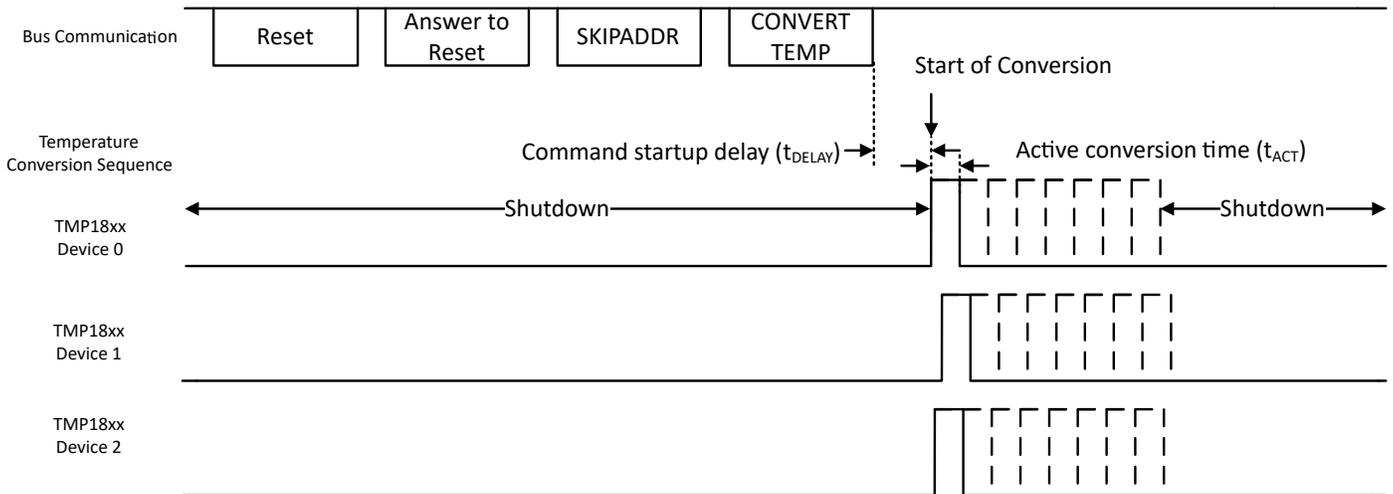


Figure 7-9. Multiple Device One-Shot Conversion Mode

7.4.1.2 Auto Conversion Mode

The auto conversion mode is a programmable feature in bus powered mode that can be enabled by setting the CONV_MODE_SEL as '10' in the [device configuration-1](#) register. As shown in [Figure 7-10](#), the host can skip the issue of the temperature conversion request and directly read the temperature data from the device when the auto conversion mode is enabled. This enables the application to speed up the temperature conversion and read, because the request command is no longer required. As in the case for multiple device bus, a low impedance current path is required to meet the current requirement of the bus during the active conversions.

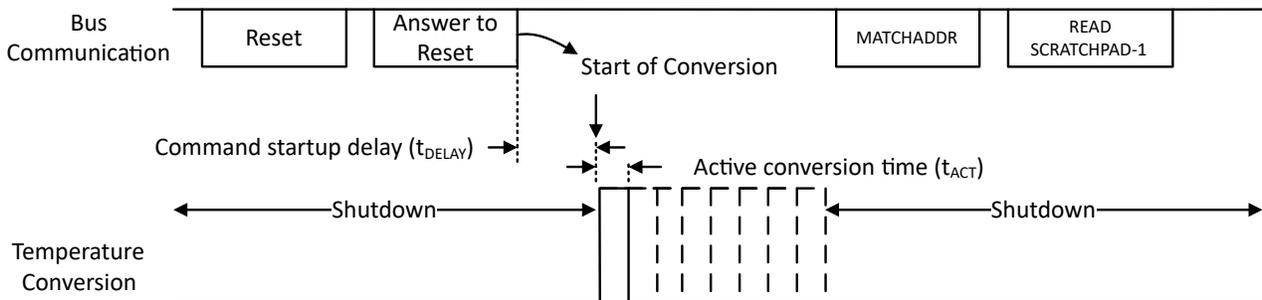
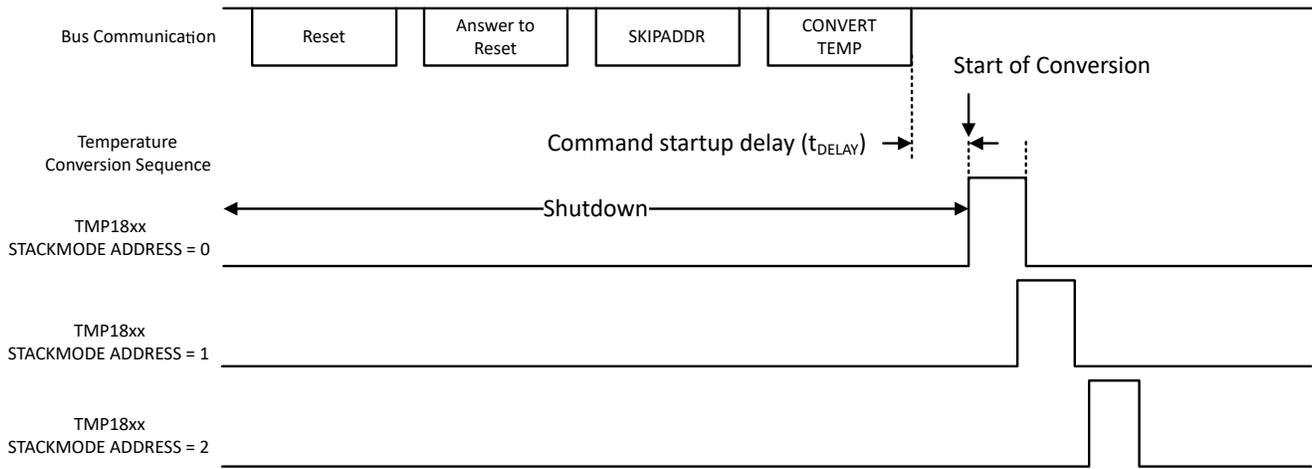


Figure 7-10. Auto Conversion Mode

7.4.1.3 Stacked Conversion Mode

The stacked conversion mode is a programmable feature in bus powered mode that can be enabled by setting CONV_MODE_SEL as '01' in the [device configuration-1](#) register. As shown in [Figure 7-11](#), the devices can use the address programmed in the [stackmode address](#) register to delay the temperature conversion for the devices when the stacked conversion mode is enabled. No more than two devices are actively converting at any given

time, therefore the current drain in bus powered configuration is limited. This allows the application to avoid simultaneous temperature conversion by multiple parts and reducing the user system maximal supply current.



Note

The host controller must program all the device with the same setting for CONV_TIME_SEL and AVG_SEL to ensure that no more than two devices are actively converting to use the feature as it is intended.

Figure 7-11. Stacked Conversion Mode

7.4.1.4 Continuous Conversion Mode

The continuous conversion mode is applicable only in V_{DD} powered mode of operation for the device. This mode can be enabled by writing a value other than '000' to CONV_MODE_SEL bits in the [device configuration-1](#) register. As shown in [Figure 7-12](#), the device can perform periodic conversions at the interval programmed by the host and updates the temperature result register when continuous conversion mode is enabled. The device also performs the alert threshold check and sets the flags and alert pin, if configured accordingly. When in continuous conversion mode, the CONVERTTEMP function has no effect on the temperature conversion request. The application can at any time change the rate of conversion or put the device back into one-shot conversion mode, and this takes effect only after the current conversion is complete.

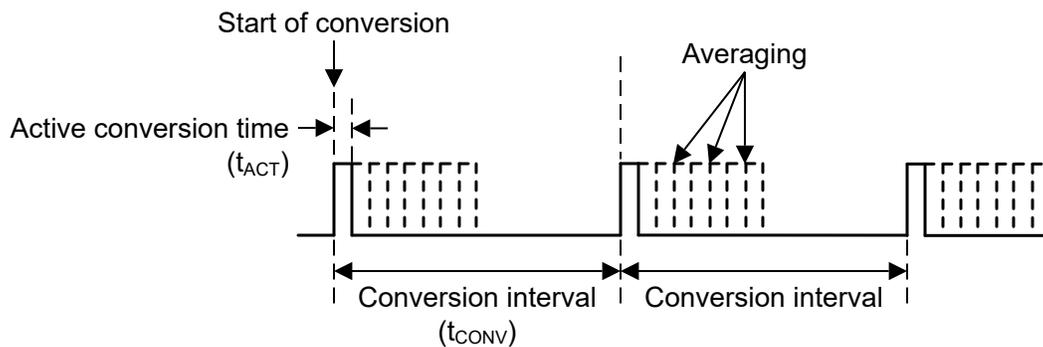


Figure 7-12. Continuous Conversion Mode

If due to any reason, the V_{DD} supply fails without the device going through a brown out, causing the device to move to bus powered mode of operation, the conversion mode automatically reverts to the setting in the configuration EEPROM.

7.4.2 Alert Function

As described earlier, the built-in alert function can be used by the host to check if the temperature has crossed a certain threshold. The alert status bits are available in both bus powered and V_{DD} powered mode. The alert pin is available only in V_{DD} powered mode.

If the device is in V_{DD} powered mode and IO2 is configured to function as an ALERT pin, then the pin shall be driven active low when the threshold crossing occurs. The pin is open-drain, and therefore requires a pullup resistor. The ALERT pin deassertion is based on the setting of the ALERT_MODE setting in the [device configuration-1](#) register.

7.4.2.1 Alert Mode

The device operates in alert mode, when the ALERT_MODE is set as '0'. In the alert mode of operation, the alert status flag and ALERT pin are asserted when the last temperature conversion is either higher than the temperature alert high limit or when it is lower than the temperature alert low limit register.

The alert status flag and ALERT pin are deasserted only when the host reads the status register or performs a successful ALERTSEARCH command as shown in [Figure 7-13](#).

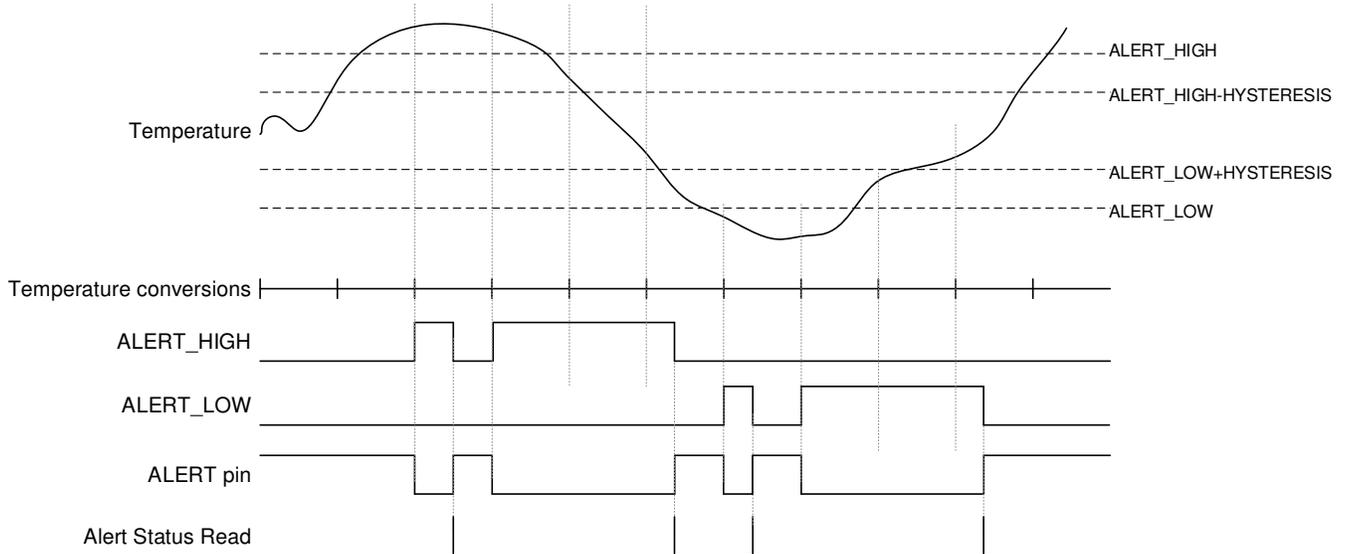


Figure 7-13. Alert Mode Timing Diagram

7.4.2.2 Comparator Mode

The device operates in comparator mode, when the ALERT_MODE is set as '1'. In the alert mode of operation, the alert status flag and ALERT pin are asserted when the last temperature conversion is either higher than the temperature alert high limit or when it is lower than the temperature alert low limit register.

The alert status flag and ALERT pin are deasserted only when the result of the last temperature conversion is less than the temperature alert high limit minus the hysteresis or above the temperature low limit plus the

hysteresis as shown in Figure 7-14. The hysteresis is selectable using the HYSTERESIS bit field in the device configuration-2 register.

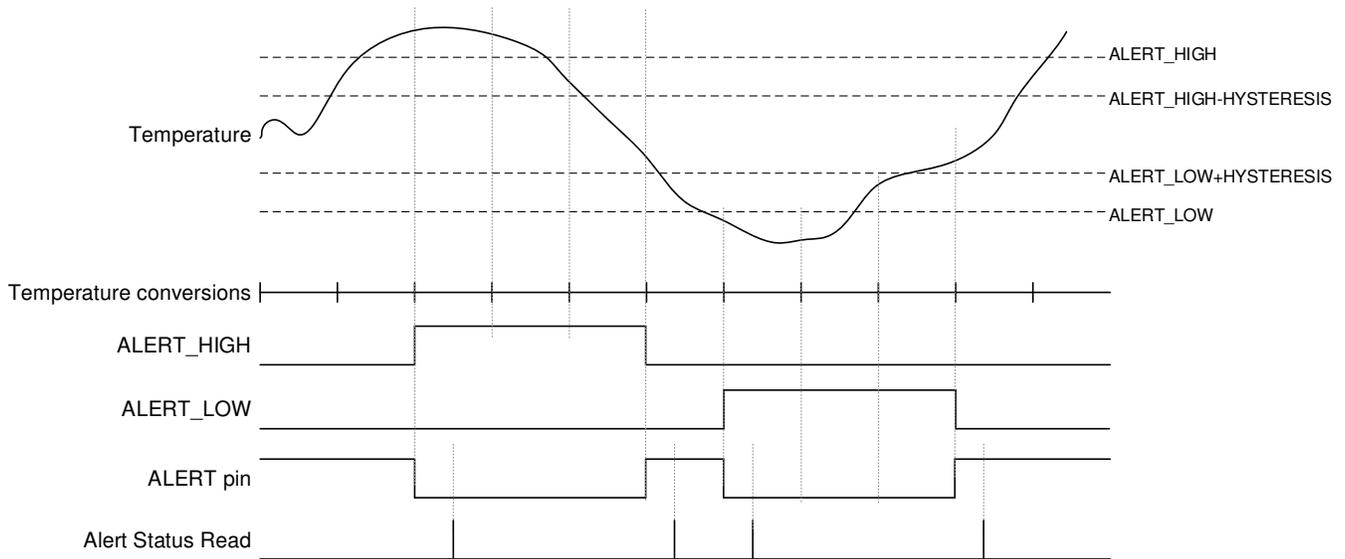


Figure 7-14. Comparator Mode Timing Diagram

7.4.3 Single-Wire Interface Communication

To leverage the features effectively, the device access consists of 3 distinct phases. As shown in Figure 7-15, any bus communication starts with a bus reset condition to which every device on the bus must respond. This is followed by a highly configurable address phase, where the host selects the device it wants to access. Finally, there is a function phase where the host provides the selected device(s) the action it wants to take.

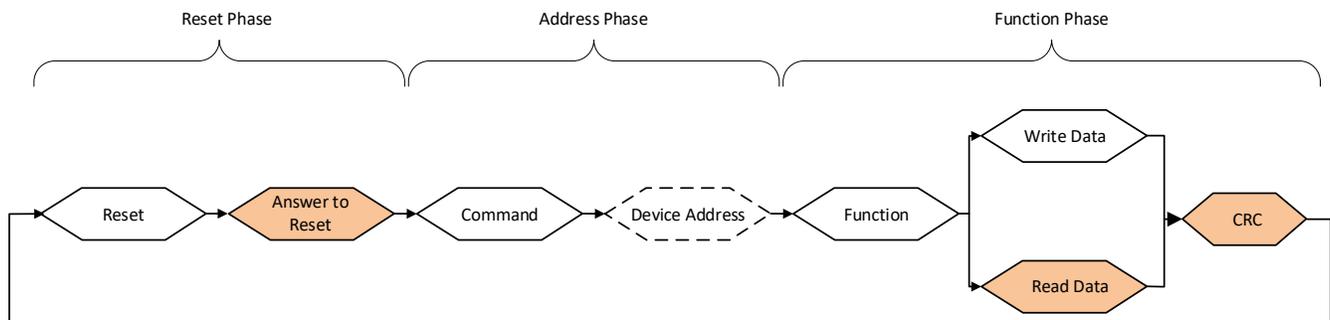


Figure 7-15. Single-Wire Bus Communication

In a single-wire bus, all write and reads are initiated by the host except for the answer to reset which is initiated by the devices on the bus.

7.4.3.1 Bus Reset Phase

The bus reset phase is the beginning of the communication. The phase is initiated by the host by holding the single-wire data line low for a period t_{RSTL} . All devices on the bus, irrespective of their current state shall respond to the bus reset, by reinitializing their internal state and responding to the host initiated bus reset. The devices respond after a minimum of t_{PDH} , by holding the single-wire low for a time period of t_{RSTH} as shown in Figure 6-1.

All devices are configured with the OD_EN bit set as '1' in the device configuration-2 register. If the host sends a bus reset pulse of 48 μ s to 80 μ s, then only devices operating in overdrive speed shall respond to the bus reset pulse, while devices operating in standard mode shall continue to wait for a standard mode bus reset.

If the host sends a bus reset pulse of minimum t_{RSTL} for standard mode, the device shall reset the OD_EN bit to '0' and respond to the bus reset in standard mode. If the bus consists of mixed standard and overdrive speed

devices, then sending a bus reset pulse in standard mode shall reset all devices to standard mode speed of operation.

It is illegal for the host to send the bus reset for a particular speed of operation and then communicate at the other speed mode. Also, if a bus reset pulse is sent which is greater than 80 μ s (but less than 480 μ s), then the device shall be reset, though the device operation is not ensured.

7.4.3.2 Address Phase

The address phase follows the bus reset phase as shown in Figure 7-16. During this phase the host presents 8-bit commands which may be followed by either host sending a 64-bit device address skipping the address. Some of the commands are used to discover the device address, while others are used to select the device.

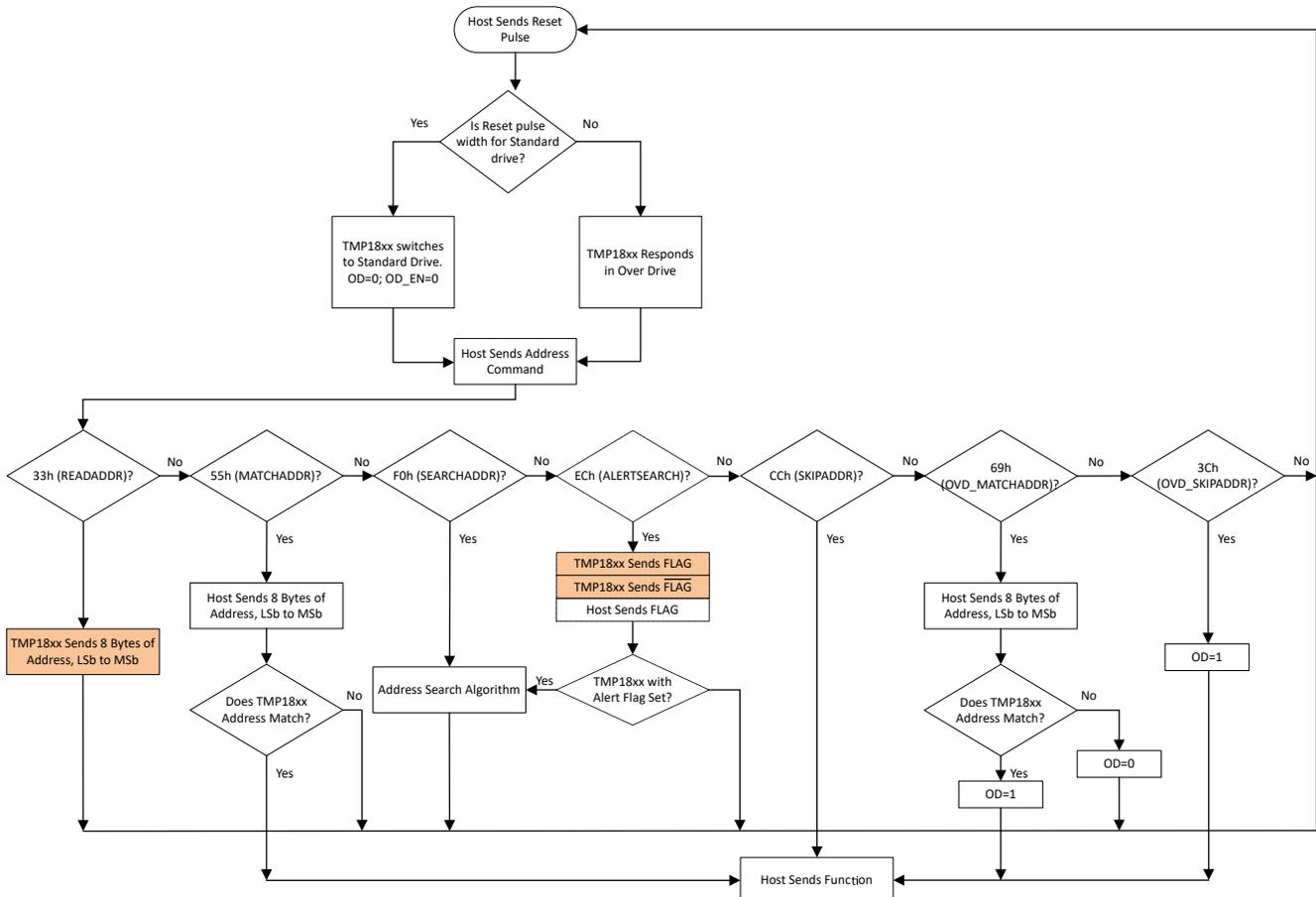


Figure 7-16. Address Phase Flowchart

7.4.3.2.1 READADDR (33h)

The command can be used by the host to read the 64-bit address of the device. This command must only be used when there is one device on the bus, as this command will cause a collision if multiple devices are present on the bus.

7.4.3.2.2 MATCHADDR (55h)

The command is used by the host and is followed by a 64-bit address that is used to select a single device on the bus. The address for each device is unique, therefore only one device can be selected by the command while all other devices continue to wait for a bus reset.

7.4.3.2.3 SEARCHADDR (F0h)

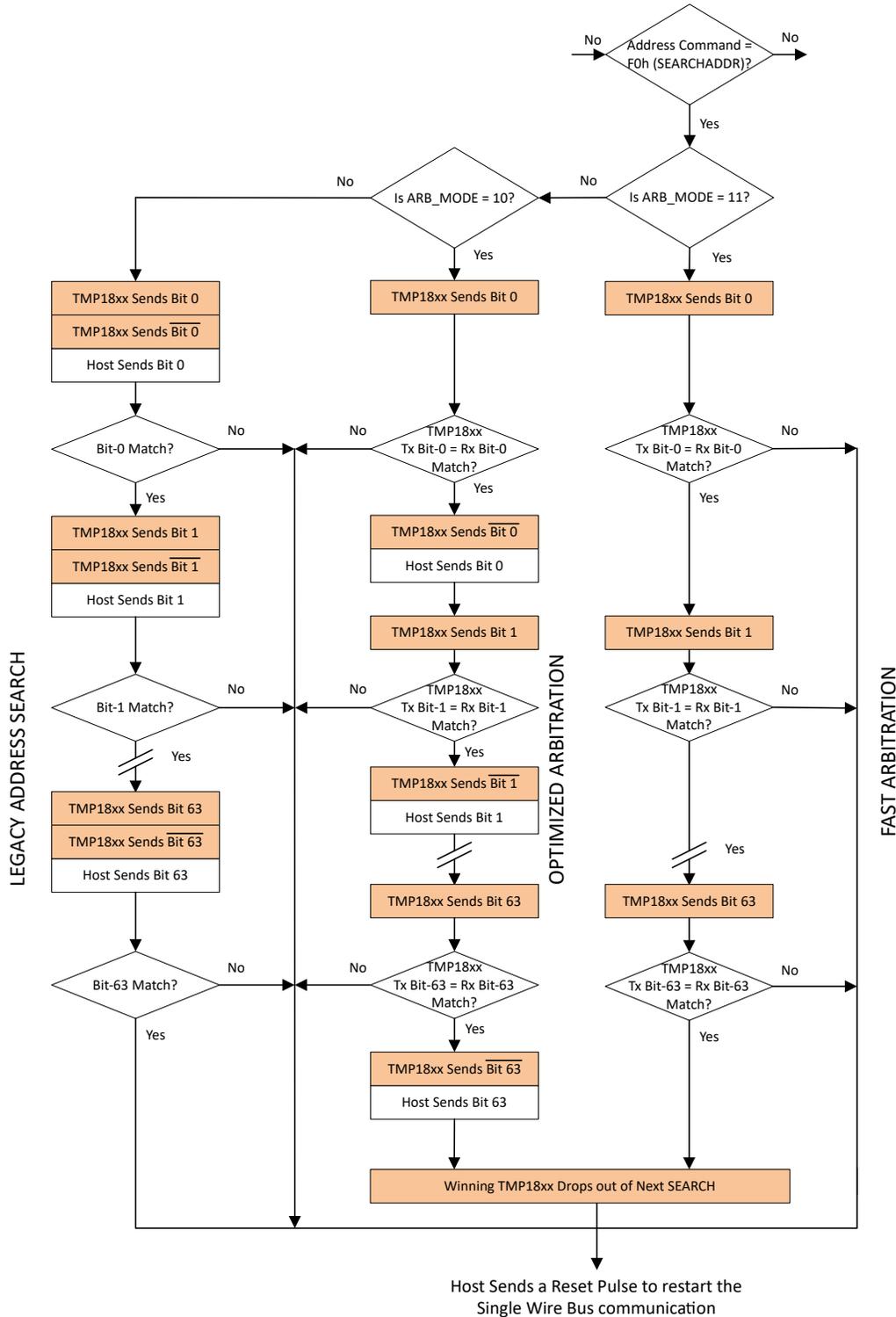
The command is used by the host to identify the 64-bit address of each of the devices on the bus after the system is powered up (see Figure 7-17). Additionally, this command may be run by the host to discover any

new devices that may be added to the system later. When there is a single device bus, the host can skip the command and instead use the SKIPADDR command to access the device.

As shown in right side flow of [Figure 7-17](#), when the fast arbitration mode is enabled by setting ARB_MODE bits as '11' in the [device configuration-2](#) register, the devices check the bus for the transmitted bit. If the device reads a bit value other than what they had transmitted, they no longer respond to the command until the next bus reset. A device that wins the bus continues until the 64th bit, after which it does not respond to the next SEARCHADDR command until the arbitration mode is reenabled. The arbitration function allows the host a fast discovery of the devices without having to go through the complicated, memory intensive and longer discovery method using traditional SEARCHADDR command. At the same time, if the host has an issue on the bus, then it can simply perform a broadcast write to disable and enable the arbitration mode to restart the fast arbitration mode.

The device also features an optimized arbitration mode which is enabled by setting ARB_MODE bits as '10'. The devices check the transmitted bit, and if the devices detect a logic '0' when they send a logic '1', they do not participate in the SEARCHADDR command until the next SEARCHADDR command is sent. The device that is able to send all 64 bits successfully, wins the bus and does not participate in the arbitration till the mode is reenabled. As a result of the optimized arbitration mode, the host does not have to manage the complex memory structure to identify devices on the bus and can still use the legacy software search algorithm.

When the host has received the address of each device on the bus, the host must disable the arbitration mode and only enable it again if the host wants to use the SEARCHADDR command again when new devices are added to an existing bus.



ADVANCE INFORMATION

Figure 7-17. Address Search Algorithm Flowchart

7.4.3.2.4 ALERTSEARCH (Ech)

The command is used by the host to identify if any of the devices have an alarm condition that must be serviced. An alarm condition is set by the device when the temperature conversion is performed and the temperature result is higher than [alert high temperature](#) register or lower than [alert low temperature](#) register. The command uses the same method as the SEARCHADDR command, except that only devices with an alarm condition shall

respond. If none of the devices have an alarm condition, then the host shall get all '1' followed by '1' on the bus and host can send a bus reset subsequently. If the device sends a '1' followed by '0', the host shall interpret it as either one or more devices have an alert condition, or all devices have an alert condition. If there is a bus noise, that causes the line to be sample erroneously, but if no device has an alert condition, then the host shall get all '1' on the bus during the address search phase.

Only devices that have an alert set shall participate when they receive an ALERTSEARCH address command and shall respond by sending its 64-bit address. A device shall no longer participate in the send address phase if it successfully transmits the device address, which automatically clears the internal alert flags, unless another temperature conversion results in the alert condition getting set.

7.4.3.2.5 SKIPADDR (CCh)

The host can issue this command to select all the devices on the bus. This is useful when the host wants to write to the scratchpad-1 or trigger the temperature conversion for all the devices on the bus. Additionally, the host can use the command to increase the overall bus data throughput when there is a single device on the bus.

The host must take care to not issue the command when there are multiple devices on the bus. If the host intended to read the devices with this command, it would cause a collision on the bus.

7.4.3.2.6 OVD SKIPADDR (3Ch)

The host can issue this command to select all devices which support overdrive speed in a mixed speed bus. This is useful when the host wants to write to the scratchpad-1 or trigger the temperature conversion for all the devices on the bus that support overdrive speeds. Additionally, the host can use the command to increase the overall bus data throughput when there is a single device on the bus. When the command is issued, only devices that support overdrive mode shall set the internal OD flag as '1'.

The host must take care to not issue the command when there are multiple devices on the bus which support overdrive mode. If the host intended to read the devices with this command, it would cause a collision on the bus.

If the host issues a standard mode bus reset at any time, all devices which have OD flag set as '1' shall clear the same and revert back to standard mode speed.

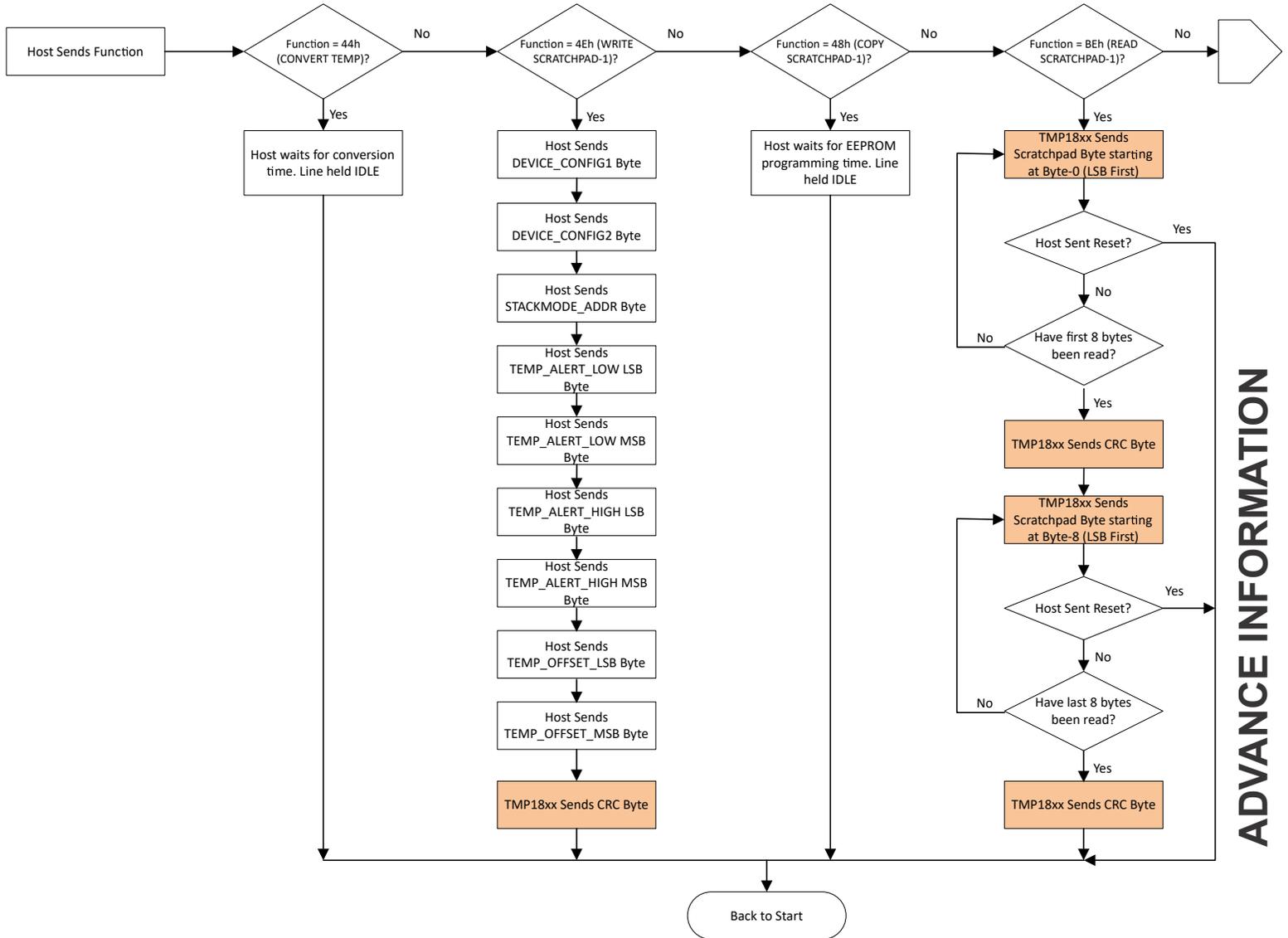
7.4.3.2.7 OVD MATCHADDR (69h)

The command is used by the host and is followed by a 64-bit address that is used to select a single device on the bus in overdrive speed. The address for each device is unique, therefore only one device can be selected by the command while all other devices have to wait for a bus reset. The selected device shall set its internal OD flag as '1', and start all further communication in overdrive speed.

If the host issues a standard mode bus reset at any time, or selects another device using the OVD MATCHADDR, then all other devices which have OD flag set as '1' shall clear the same and revert back to standard mode speed.

7.4.3.3 Function Phase

The function phase follows the address phase as shown in [Figure 7-18](#), [Figure 7-19](#) and [Figure 7-20](#). The host may present different functions during this phase, which is followed by either the host sending data to the device, reading device data, or starting a temperature conversion. Some of the functions may be broadcast to all the devices on the bus using SKIPADDR or OVD SKIPADDR. Read functions must always be unicast with a device selected during the address phase using MATCHADDR or OVD MATCHADDR. For cases, where there is a single device on the bus, the device address selection may be skipped.



ADVANCE INFORMATION

Figure 7-18. Function Phase Flowchart for Register Space

7.4.3.3.1 CONVERTTEMP (44h)

The function is issued by the host when the host wants the temperature sensors on the bus to perform a one-shot temperature conversion.

When the device is bus powered, the host must keep the bus idle for the duration of the active temperature conversion. The active temperature conversion time is dependent on the conversion mode. After temperature conversion has completed, the result is updated in [temperature result LSB](#) and [temperature result MSB](#) registers.

When automatic temperature conversion mode is enabled in the [device configuration-1](#) register, the command may be skipped altogether, allowing faster access to the temperature result.

7.4.3.3.2 WRITE SCRATCHPAD-1 (4Eh)

The function is issued by the host to write the functional register for the temperature sensor. Following the function byte, the host transmits the device configuration registers, stackmode address register, temperature alert low limit registers, temperature alert high limit registers and temperature offset registers. After sending the 9 bytes, the device shall transmit the CRC computed on the 9 bytes and send the CRC back to the host for quick verification of data integrity.

Additionally, the host can issue a bus reset at any time during the transfer, though it is advised that the same may be done only at byte boundary to ensure that there is no register corrupted due to incomplete transfer.

Note

When updating the OD_EN and/or LOCK_EN bit in the device configuration-2 register, the host controller must send the 9 bytes and wait for the CRC transmission before the change of device speed or write protection of the register scratchpad can take effect. If the host terminates the transfer before the complete CRC transmission, then any update to OD_EN and/or LOCK_EN shall not take effect.

7.4.3.3.3 READ SCRATCHPAD-1 (BEh)

The function is issued by the host to read the temperature result, status bits, and functional registers from the register scratchpad. The selected device transmits the first 8 bytes of the register scratchpad followed by CRC of the 8 bytes. If the host wants to continue the read operation, the host will receive the next 8 bytes along with CRC for the last 8 bytes. The host can terminate the function at any point by issuing a bus reset.

7.4.3.3.4 COPY SCRATCHPAD-1 (48h)

The function is issued by the host to copy the functional registers content to the EEPROM. As shown in Figure 7-18, the temperature alert registers, configuration register, stackmode address register, and temperature offset registers are stored in the configuration EEPROM. There are 9 bytes being copied from the register space to the NVM, therefore the host must hold the bus in idle state for twice the EEPROM programming time before it performs the next access.

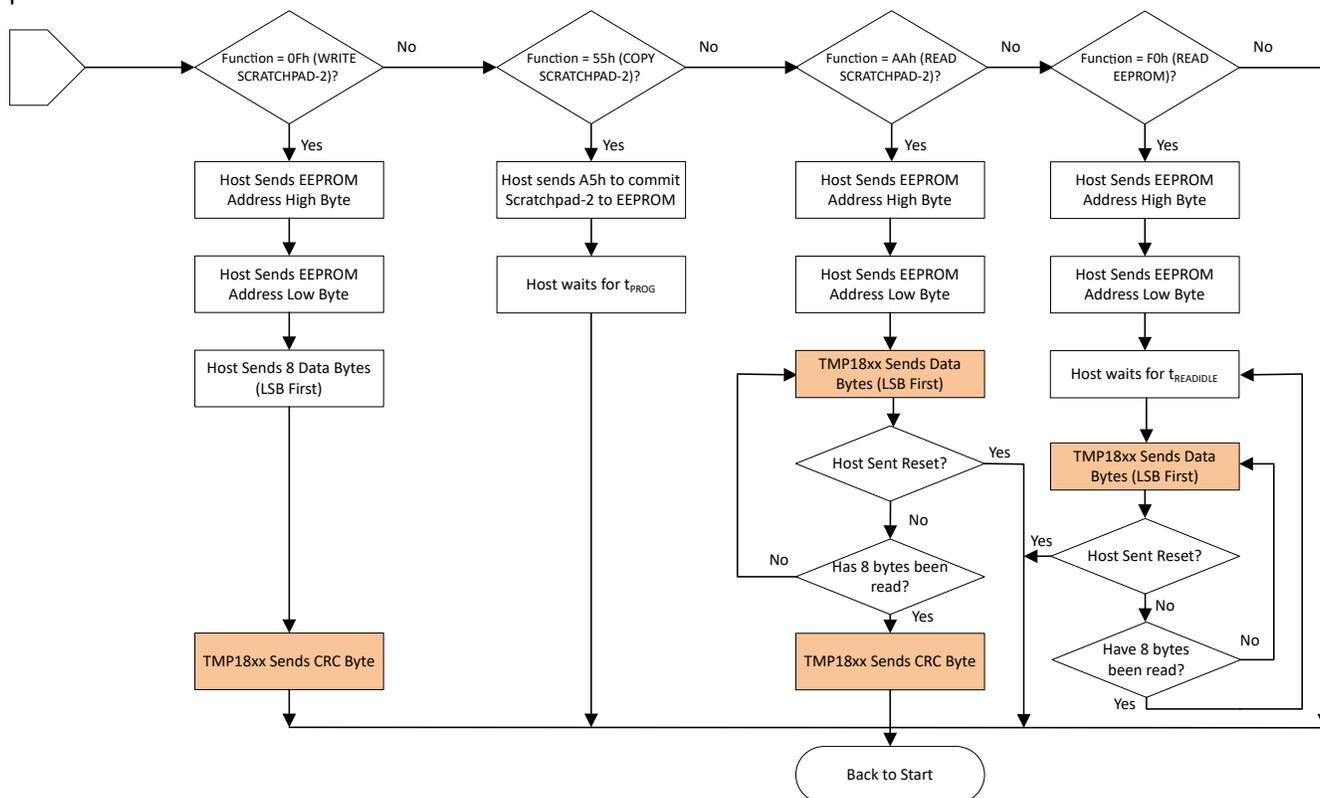


Figure 7-19. Function Phase Flowchart for Memory Access

7.4.3.3.5 WRITE SCRATCHPAD-2 (0Fh)

The function is issued by the host to prepare data write to the EEPROM using memory scratchpad.

The host first sends the 2 bytes for the EEPROM address as shown in Figure 7-19, followed by the 8 data bytes. On receiving the 8 data bytes, the device computes the CRC for total of 10 bytes of address and data received from the host for data integrity check. The function only copies the data to the memory scratchpad, to enable the

host to change data, before the final EEPROM erase and program. Additionally, the host may use the memory scratchpad as a 8-byte volatile buffer.

The device does not support byte wise access for EEPROM. All access to the scratchpad are done in increments of 8 bytes. Hence the host must send the address at the 8-byte block boundary. Any attempt to write data at a non-block boundary shall result in data being corrupted in the corresponding EEPROM page and block as shown in [Figure 7-5](#).

7.4.3.3.6 READ SCRATCHPAD-2 (AAh)

The function is issued by the host to read the content of the memory scratchpad.

The host first sends the 2 bytes for the EEPROM address (see [Figure 7-19](#)). If the 2 bytes of address matches the address sent during the last WRITE SCRATCHPAD-2, the device responds by sending the 8 bytes of data that was written to the scratchpad-2 buffer earlier. The host can send a bus reset any time during the transfer. If the device sends all 8 bytes and no bus reset is received, the device transmits the CRC computed on the 2 byte of address sent by the host and 8 bytes of data sent by the device to the host for data integrity check.

If there is a mismatch in the address, the device shall go back to the start and wait for a bus reset to restart communication, and the host shall receive '1' on the bus for any subsequent read. This mechanism ensures that the host can detect an address byte corruption during both WRITE SCRATCHPAD-2 and READ SCRATCHPAD-2, as both the data bytes and CRC byte will read back as FFh.

7.4.3.3.7 COPY SCRATCHPAD-2 (55h)

The function is issued by the host to copy the contents of scratchpad-2 to the EEPROM. The EEPROM current is higher during the erase and program, therefore the application must size the external pullup resistor to ensure that there is sufficient current drawn by the multiple devices or implement a low impedance current path using an external FET/transistor switch parallel to the bus pullup resistor.

The host application must ensure that only WRITE SCRATCHPAD-2 or READ SCRATCHPAD-2, with address of the intended location in the user EEPROM, are issued before COPY SCRATCHPAD-2 is sent. The device stores and uses the address sent during WRITE SCRATCHPAD-2 to identify the location in the user EEPROM where the copy operation shall be performed. The host only needs to send one byte with A5h to initiate the copy of the memory content from scratchpad-2 to the user EEPROM, at the address location already specified, when performing the commit operation. The host must hold the bus in idle state for the EEPROM programming time before starting any new access on the bus.

7.4.3.3.8 READ EEPROM (F0h)

The function is issued by the host to read the EEPROM memory directly.

The host sends 2 bytes for the address of the EEPROM location, that it wants to read. The device then sends the data bytes starting from that location until the internal address pointer does not reach the end of the EEPROM or host does not issue a bus reset. If the internal address pointer reaches end of the EEPROM location, the device shall send 1's on the bus. After sending the 2 bytes for the address of the EEPROM location to access, and when moving between block boundary, the host must idle the bus for t_{IDLE} as specified in the EEPROM characteristics. Additionally, there is no CRC provided in the response from the device during the READ EEPROM function.

The device does not support byte wise access for EEPROM. All access to the memory is done in increments of 8 bytes. Hence the host must send the address at the 8-byte block boundary. Any attempt to read data to

the scratchpad at a non-block boundary shall result in data being sent from the start of the block boundary corresponding to the address as shown in Figure 7-5.

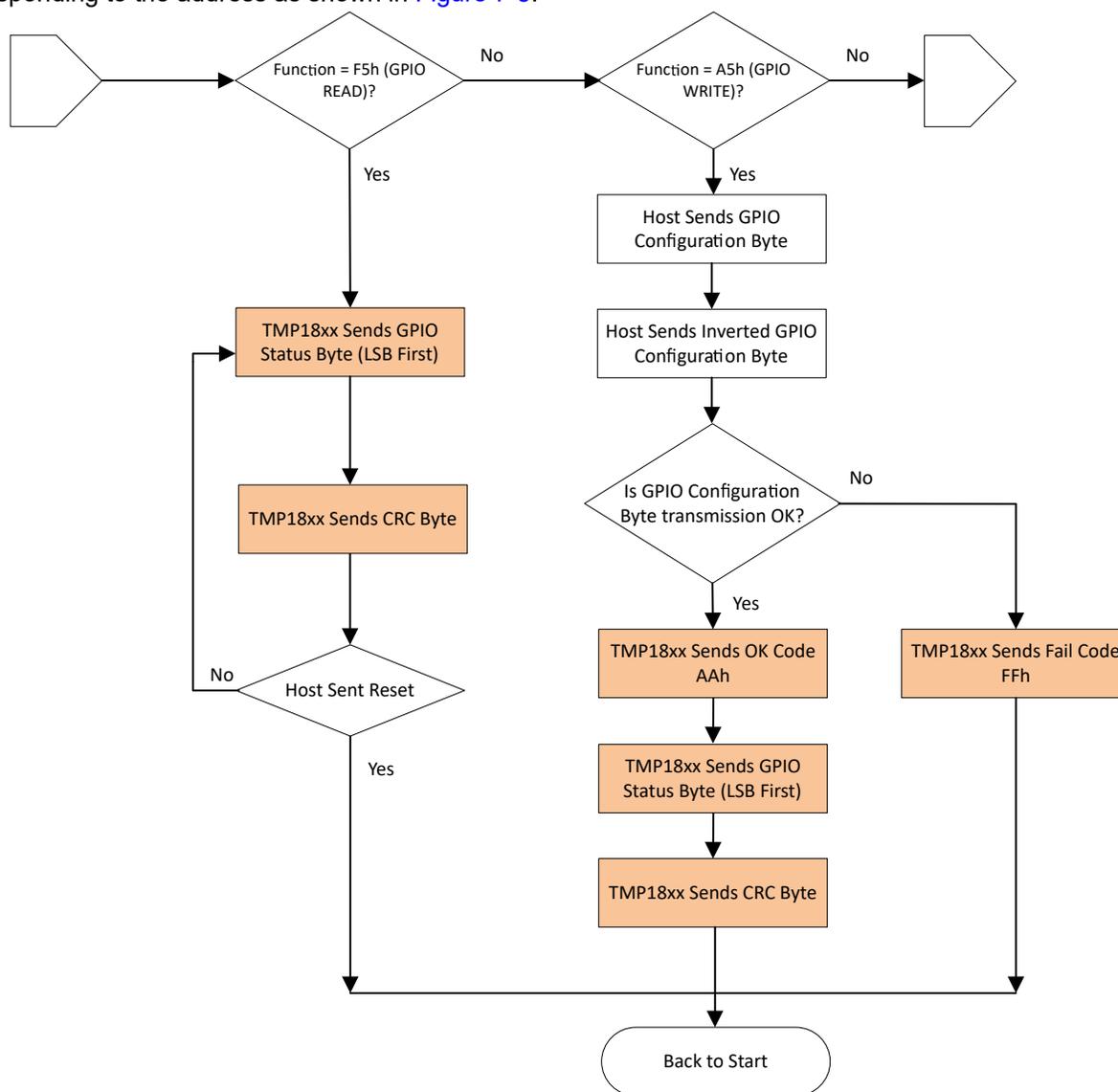


Figure 7-20. Function Phase Flowchart for IO Access

7.4.3.3.9 GPIO WRITE (A5h)

The function is issued by the host to configure and read the GPIO.

The host sends the **IO configuration** byte, followed by the inverted IO configuration byte value. This enables the device to check for bit error due to bus noise. If there are errors detected, then the device shall transmit a fail code of FFh to the host, for the host to retry. If there are no errors detected, then the device shall transmit the success code of AAh. The host may issue a bus reset and terminate the transaction or may proceed to read of the IO state, where the device shall send the **IO read** byte, followed by the CRC byte for the IO status byte.

The host must send a bus reset to terminate the function and bring the device back to its idle state.

7.4.3.3.10 GPIO READ (F5h)

The function is issued by the host to read the GPIO.

After issuing the function, the device sends a byte which has the corresponding IO status, followed by the CRC for the IO status byte. The host may repeat the sequence or may send a bus reset to terminate the function.

7.4.4 NVM Operations

The TMP1826 device follows a common procedure for programming user data and enabling the memory protection for user data.

7.4.4.1 Programming User Data

Programming of user data to the memory use the functions WRITE SCRATCHPAD-2, READ SCRATCHPAD-2 and COPY SCRATCHPAD-2 as described earlier. The application must use the address in the provided [functional memory map](#) to write user data to the device.

1. Host issues a bus reset, then waits for the response and sends the address command for the specific device.
2. Host issues a WRITE SCRATCHPAD-2 with the address as per the functional memory map and the 8 bytes of data.
3. Host issues a bus reset, then waits for the response and sends the address command for the specific device.
4. Host issues a READ SCARTCHPAD-2 with the address as per the functional memory map, then reads the 8 bytes of data to ensure that it is same as what was written in the earlier step.
5. Host issues a bus reset, then waits for the response and sends the address command for the specific device.
6. Host issues a COPY SCRATCHPAD-2 with the data bytes as A5h to commit the data to user EEPROM.

7.4.4.2 Register and Memory Protection

The TMP1826 provides user configurable protection for both the register scratchpad and the memory region as described below.

7.4.4.2.1 Register Protection

The device provides for a one-time write protection for the entire register map. All the writable registers, except for IO configuration, can be write-protected. To enable the write protection permanently, the host controller must set LOCK_EN bit in the [device configuration-2](#) register, then copy the register to the configuration EEPROM. When the configuration EEPROM is programmed, the change is permanent and irreversible.

Additionally, the device provides temporary write protection mechanism. If the LOCK_EN bit is not committed to configuration EEPROM, the device shall prevent any write to the register scratchpad-1 region as long as power is applied. If the device goes through a POR, then the LOCK_EN bit shall be cleared to allow the host to update the register scratchpad-1.

7.4.4.2.2 User Memory Protection

The device provides a configurable one-time memory protection mechanism. Memory protection is available at page level of 32 bytes of 256 bits. There are two levels of memory protection that are available on the TMP1826:

- Public Read and Write: This is default memory option for factory-programmed parts. The host controller can read and write without any additional steps.
- Public Read with write protection: In this mode, the host controller can read the memory without any specific steps, but write access is not allowed.

Each page can be protected using a special address described below:

Table 7-3. User Memory Protection

USER MEMORY PROTECTION ADDRESS		COMMENTS
PROTECTION LEVEL OPERAND	PAGE NUMBER FIELD	
80h	00h	User memory page-0 cannot be erased and programmed in any mode. Public mode read access is allowed.
80h	01h	User memory page-1 cannot be erased and programmed in any mode. Public mode read access is allowed.
80h	02h	User memory page-2 cannot be erased and programmed in any mode. Public mode read access is allowed.

Table 7-3. User Memory Protection (continued)

USER MEMORY PROTECTION ADDRESS		COMMENTS
PROTECTION LEVEL OPERAND	PAGE NUMBER FIELD	
80h	03h	User memory page-3 cannot be erased and programmed in any mode. Public mode read access is allowed.
80h	04h	User memory page-4 cannot be erased and programmed in any mode. Public mode read access is allowed.
80h	05h	User memory page-5 cannot be erased and programmed in any mode. Public mode read access is allowed.
80h	06h	User memory page-6 cannot be erased and programmed in any mode. Public mode read access is allowed.
80h	07h	User memory page-7 cannot be erased and programmed in any mode. Public mode read access is allowed.

ADVANCE INFORMATION

The memory protection bits can be programmed only one time. Hence after a page is locked, it cannot be unlocked. The method to lock a user memory page in public read-only with write protection is described in the following sequence:

1. Host issues a bus reset, then waits for the response and sends the address command for the specific device.
2. Host issues a WRITE SCRATCHPAD-2 with the address as 80XXh, where XX is the page number, and data byte as 55h.
3. Host issues a bus reset, then waits for the response and sends the address command for the specific device.
4. Host issues a READ SCRATCHPAD-2 with the address as 80XXh, where the XX is the page number and reads the data byte to ensure it is 55h.
5. Host issues a bus reset, then waits for the response and sends the address command for the specific device.
6. Host issues a COPY SCRATCHPAD-2 with the data byte as A5h to commit the protection for the page.

7.5 Programming

The TMP1826 has multiple methods in which an application can access the device functions for temperature conversion and EEPROM programming. When accessing multiple device the MATCHADDR command must be used.

The sections below describe the sequences that must be followed to access the device functions properly.

7.5.1 Single Device Temperature Conversion and Read

Figure 7-21 shows the program flow that the host MCU must execute for temperature conversion and subsequent read of the temperature result. As the temperature results are the first two bytes of the register scratchpad, the host may optionally stop the read after the device transmits the first two bytes by performing a bus reset.



Figure 7-21. Single Device Temperature Conversion and Read Programming Flow

7.5.2 Multiple Device Temperature Conversion and Read

Figure 7-22 shows the program flow that the host MCU must execute for temperature conversion and subsequent read of the temperature result for multiple devices. The host must use the MATCHADDR command to address each device on the bus, because the devices do not arbitrate on a read function.

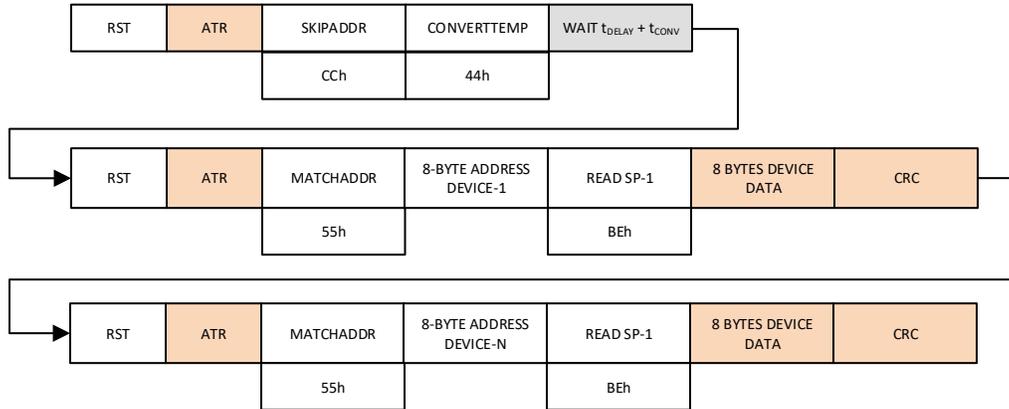


Figure 7-22. Multiple Device Temperature Conversion and Read Programming Flow

7.5.3 Register Scratchpad Update and Commit

Figure 7-23 shows the sequence the host must execute to update the register scratchpad and commit to the configuration EEPROM. The host must read the scratchpad to ensure it can perform the correct read modify write to the register locations, before it commits the same to the configuration EEPROM.

If the host has only one device, or if the application can guarantee no bus corruption, then it may use SKIPADDR command to globally update and commit the register scratchpad region. However once committed and locked, it is not possible for the host to update the locations anymore, and hence TI strongly advises that the host still read the locations before running the commit operation.

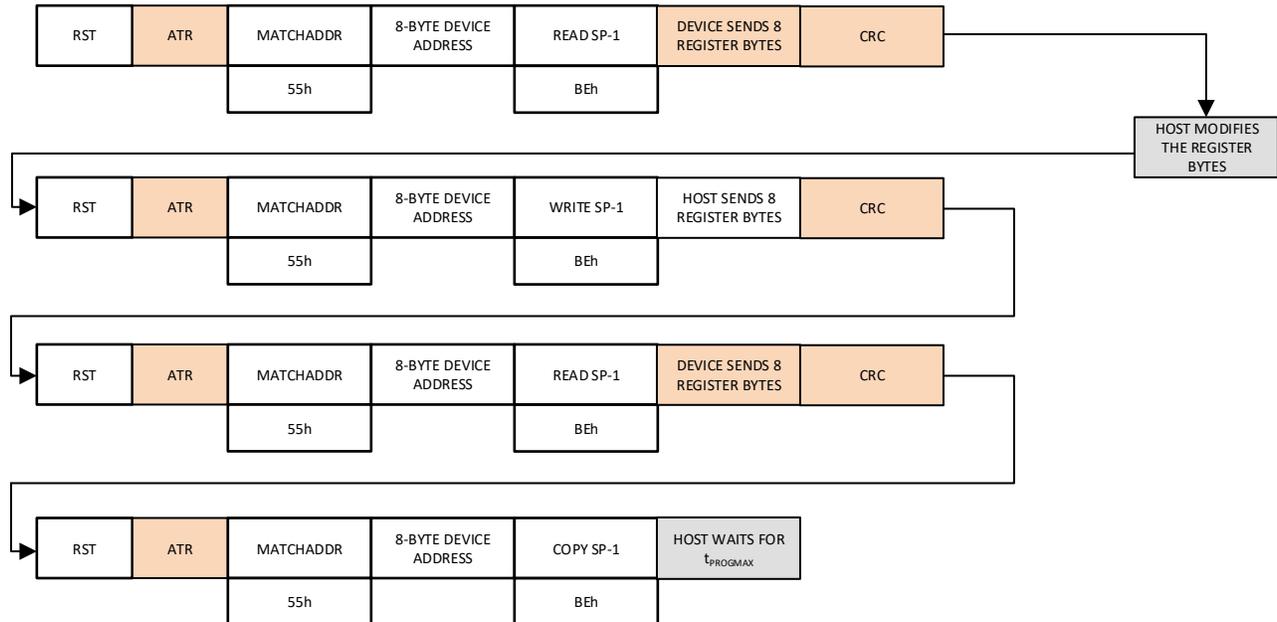


Figure 7-23. Register Scratchpad Update and Commit Programming Flow

7.5.4 Single Device EEPROM Programming and Verify

Figure 7-24 shows the correct procedure the host must execute to update the EEPROM. When communicating with a single device, the host may use the SKIPADDR command. However when communicating with multiple devices, the host must use the MATCHADDR command to address the correct device. The host writes to the EEPROM scratchpad first, then reads it back to verify the content before it commits the same to the user EEPROM. The host shall repeat the sequence for every 8 byte page. After the locations are programmed, the host may issue an READ EEPROM function with the start address to read all the bytes. The device shall read back the bytes in page size and put a CRC byte after every page to ensure that the host shall be able to identify bit corruption using the CRC over a smaller data packet.

As long as the host continues the read operation, the device shall read back 8 bytes of data followed by a CRC byte. When the device reaches the end of the EEPROM block, the device shall return all 1's to the host.

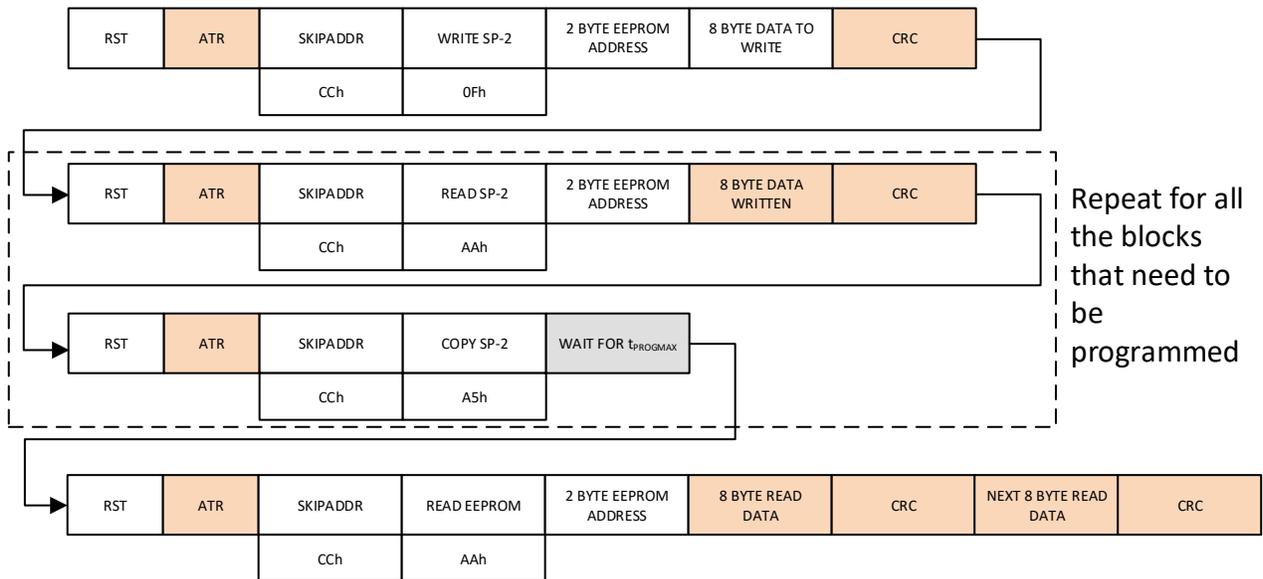


Figure 7-24. Single Device EEPROM Programming and Verify Flow

7.5.5 Single Device EEPROM Lock Operation

When the device EEPROM is successfully programmed as shown in Figure 7-24, the host shall execute the sequence, as shown in Figure 7-25, to write-protect the EEPROM block.

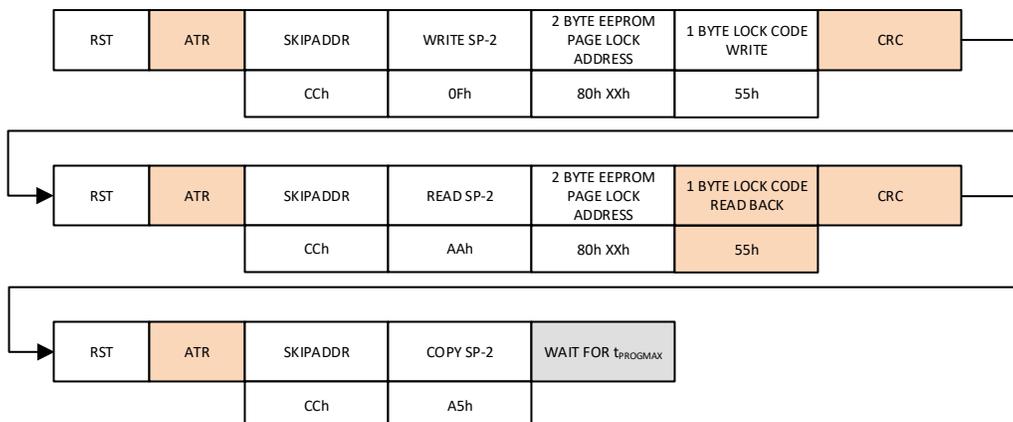


Figure 7-25. Single Device EEPROM Lock Operation Flow

7.5.6 Multiple Device IO Read

Figure 7-26 shows the program flow that the host MCU must execute for reading the IO from a device. The host selects the device it wants to communicate with and issues the GPIO READ function. The host must wait for the time it takes for the device to sample the IO, by keeping the bus idle, before the device returns the IO read register value along with the CRC for the byte. The device at this point shall again sample the IOs. If the host issues a bus reset during the sampling time, the device shall terminate the update process and it will hold the last sampled value. If the host continues, then the new sampled values shall be sent back by the device.

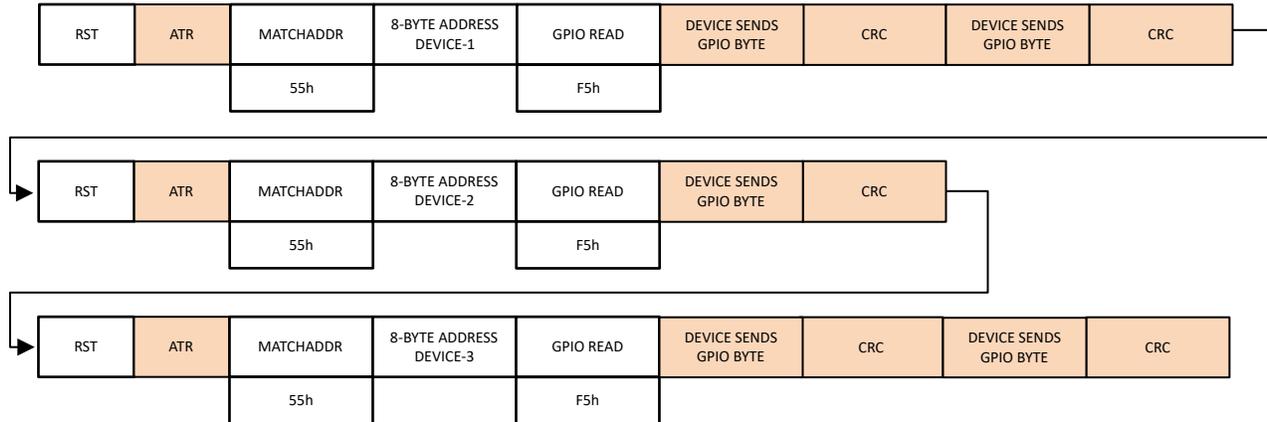


Figure 7-26. Multiple Device GPIO Read Flow

7.5.7 Multiple Device IO Write and Read

Figure 7-27 shows the program flow that the host MCU must execute for configuring the and reading the IO from a device. The host selects the device it wants to communicate with and issues the GPIO WRITE function. The host shall then send the IO configuration register followed by an inverted value, that allows the device to check for any bus transmission error. If the host receives a return code any other than AAh, it must terminate the transaction by sending a bus reset. When the host gets the return code of AAh from the device, it shall wait for the device to sample the bus and then read back the IO read register along with a CRC. If the host plans to read the device continuously, then it must send a bus reset and initiate a GPIO READ function.

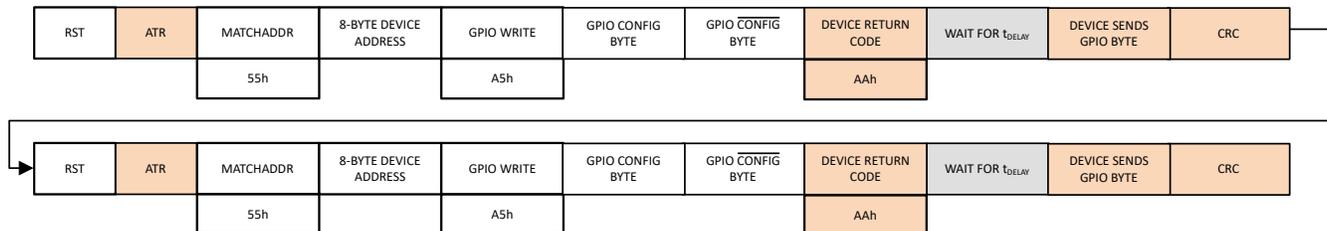


Figure 7-27. Multiple Device GPIO Write and Read Flow

7.6 Register Maps

Table 7-4. Register Map

SCRATCHPAD-1 BYTE	TYPE	RESET	REGISTER NAME	REGISTER DESCRIPTION	SECTION
00h	RO	80h	TEMP_RESULT_L	Temperature result LSB register	Go
01h	RO	0Ch	TEMP_RESULT_H	Temperature result MSB register	Go
02h	RO	3xh	STATUS_REG	Status register	Go
03h	RO	FFh	Reserved	Reserved	
04h	R/W	70h	CONFIG_REG1	Device Configuration-1 register	Go
05h	R/W	80h	CONFIG_REG2	Device Configuration-2 register	Go

Table 7-4. Register Map (continued)

SCRATCHPAD-1 BYTE	TYPE	RESET	REGISTER NAME	REGISTER DESCRIPTION	SECTION
06h	R/W	00h	STACKMODE_ADDR	Stackmode address register	Go
07h	RO	FFh	Reserved	Reserved	
08h	R/W	00h	TEMP_ALERT_LOW_L	Temperature alert low limit LSB	Go
09h	R/W	00h	TEMP_ALERT_LOW_H	Temperature alert low limit MSB	Go
0Ah	R/W	F0h	TEMP_ALERT_HIGH_L	Temperature alert high limit LSB	Go
0Bh	R/W	07h	TEMP_ALERT_HIGH_H	Temperature alert high limit MSB	Go
0Ch	R/W	00h	TEMP_OFFSET_L	Temperature offset calibration LSB register	Go
0Dh	R/W	00h	TEMP_OFFSET_H	Temperature offset calibration MSB register	Go
0Eh	RO	FFh	Reserved	Reserved	
0Fh	RO	FFh	Reserved	Reserved	
—	RO	F0h	IO_READ	IO read register	Go
—	RW	00h	IO_CONFIG	IO configuration register	Go

Table 7-5. Access Type Codes

Access Type	Code	Description
Read Type		
R	R	Read
RC	R C	Read to Clear
R-0	R -0	Read Returns 0s
Write Type		
W	W	Write
W0CP	W 0C P	W 0 to clear Requires privileged access
Reset or Default Value		
-n		Value after reset or the default value

7.6.1 Temperature Result LSB Register (Scratchpad-1 offset = 00h) [reset = 80h]

The register is part of the 16-bit temperature result readout that stores the least significant byte of the output of the most recent conversion. Following a power up, the register has the value 80h until the first conversion is complete.

Return to [Register Map](#).

Figure 7-28. Temperature Result LSB Register

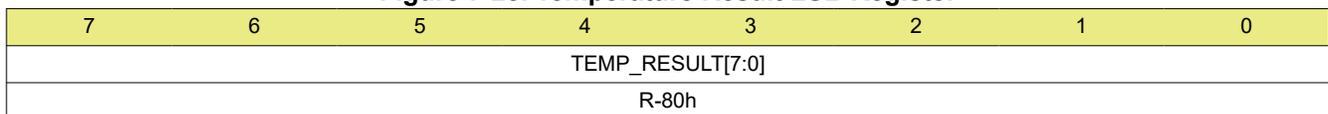


Table 7-6. Temperature Result LSB Register Field Descriptions

Bit	Field	Type	Reset	Description
7:0	TEMP_RESULT[7:0]	R	80h	Stores the LSB of the most recent temperature conversion results.

7.6.2 Temperature Result MSB Register (Scratchpad-1 offset = 01h) [reset = 0Ch]

The register is part of the 16-bit temperature result readout that stores the most significant byte of the output of the most recent conversion. Following a power up, the register has the value 0Ch until the first conversion is complete.

Return to [Register Map](#).

Figure 7-29. Temperature Result MSB Register

7	6	5	4	3	2	1	0
TEMP_RESULT[15:8]							
R-0Ch							

Table 7-7. Temperature Result MSB Register Field Descriptions

Bit	Field	Type	Reset	Description
7:0	TEMP_RESULT[15:8]	R	0Ch	Stores the MSB of the most recent temperature conversion results.

7.6.3 Status Register (Scratchpad-1 offset = 02h) [reset = 3Ch]

This register provides status of the alert flags, power mode, arbitration completion, and device lock. The lock flag is set after the device configuration EEPROM is locked by the application. The arbitration done flag is set after the device successfully sends its device address and is cleared only when the ARB_MODE bits in the configuration register are cleared. The power mode status flag value is decided based on the powering technique used for the device detected at power up.

The alert flags are set after the most recent conversion results are available and cleared when the status register is read by the host application. If the alert flag is set, it cannot be cleared by the device even if the result of the last conversion is between the alert limits.

Return to [Register Map](#).

Figure 7-30. Status Register

7	6	5	4	3	2	1	0
ALERT_HIGH	ALERT_LOW	Reserved			POWER_MODE	ARB_DONE	LOCK_STATUS
RC-0b	RC-0b	R-111b			R-0b	R-0b	R-0b

Table 7-8. Status Register Field Description

Bit	Field	Type	Reset	Description
7	ALERT_HIGH	RC	0b	Alert high status flag 0b = Last temperature conversion result is less than alert high limit 1b = Last temperature conversion result is more than or equal to alert high limit
6	ALERT_LOW	RC	0b	Alert low status flag 0b = Last temperature conversion result is more than alert low limit 1b = Last temperature conversion result is less than or equal to alert low limit
5:3	Reserved	R	111b	Reserved
2	POWER_MODE	R	xb	Device power mode flag. 0b = V _{DD} powered mode 1b = Bus powered mode
1	ARB_DONE	R	0b	Arbitration complete flag 0b = Arbitration is not complete or not enabled 1b = Arbitration is complete

Table 7-8. Status Register Field Description (continued)

Bit	Field	Type	Reset	Description
0	LOCK_STATUS	R	0b	Lock status flag. 0b = Device configuration registers can be updated 1b = Device configuration registers cannot be updated

7.6.4 Device Configuration-1 Register (Scratchpad-1 offset = 04h) [reset = 70h]

The register is used to configure the device functions like the number of valid bits in temperature readout, alert mode, averaging, and conversion type (one-shot, auto and stacked conversion in bus powered mode and one-shot or continuous conversion in V_{DD} powered mode). The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Figure 7-31. Device Configuration-1 Register

7	6	5	4	3	2	1	0
TEMP_FMT	Reserved	CONV_TIME_SEL	ALERT_MODE	AVG_SEL	CONV_MODE_SEL[2:0]		
RW-0b	RW-1b	RW-1b	RW-1b	RW-0b	RW-000b		

Table 7-9. Device Configuration-1 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	TEMP_FMT	RW	0b	Selects the temperature format. 0b = 12-bit legacy format 1b = 16-bit high precision format
6	Reserved	RW	1b	Reserved
5	CONV_TIME_SEL	RW	1b	Selects the ADC conversion time 0b = 3 ms / 1b = 5.5 ms
4	ALERT_MODE	RW	1b	Alert pin function only available in V_{DD} powered mode 0b = Alert pin works in Alert Mode 1b = Alert pin works in Comparator Mode
3	AVG_SEL	RW	0b	Conversion averaging selection 0b = No averaging 1b = Averaging of 8 conversions
2:0	CONV_MODE_SEL[2:0]	RW	000b	Conversion mode selection bits. When device is in bus powered mode: 000b = Default one shot conversion mode using CONVERT TEMP function 001b = Stacked conversion mode is enabled. When enabled, the stackmode address is used to stagger the actual conversion start with respect to the conversion request. 010b = Auto temperature conversion mode is enabled 011b - 111b = Reserved. Device behavior is unspecified. When device is in V_{DD} powered mode: 000b = Default one shot conversion mode using CONVERT TEMP function 001b = One conversion every 8 seconds 010b = One conversion every 4 seconds 011b = One conversion every 2 seconds 100b = One conversion every 1 second 101b = One conversion every 0.5 second 110b = One conversion every 0.25 second 111b = One conversion every 0.125 second

7.6.5 Device Configuration-2 Register (Scratchpad-1 offset = 05h) [reset = 80h]

This register is used to configure the overdrive enable, arbitration mode during address discovery, and the hysteresis for alert status or pin (available only in V_{DD} powered mode for alert pin). The register can be used to

lock the writable registers for the device. The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Note

- When setting the overdrive enable or lock enable bits, the application must send all the scratchpad-1 data bytes and read the CRC from the device before the change of overdrive bit takes effect.

Return to [Register Map](#).

Table 7-10. Device Configuration-2 Register

7	6	5	4	3	2	1	0
OD_EN	Reserved		ARB_MODE[1:0]		HYSTERSIS[1:0]		LOCK_EN
RW-1b	RW-00b		RW-00b		RW-00b		RW-0b

Table 7-11. Device Configuration-2 Register Field Descriptions

Bit	Field	Type	Reset	Description
7	OD_EN	RW	1b	Overdrive mode enable 0b = Over drive speed is disabled 1b = Overdrive speed is enabled The bit when set cannot be cleared by host write and will automatically be cleared only by a standard speed bus reset.
6:5	Reserved	RW	00b	Reserved
4:3	ARB_MODE[1:0]	RW	00b	Arbitration mode 00b = Arbitration by device is disabled 01b = Reserved 10b = Arbitration by device is enabled in software compatible mode 11b = Fast Arbitration mode is enabled The arbitration feature is applicable only when address command is SEARCHADDR. Other commands and functions are not affected by the ARB_MODE bit.
2:1	HYSTERSIS[1:0]	RW	00b	Alert hysteresis selection 00b = 5 °C hysteresis 01b = 10 °C hysteresis 10b = 15 °C hysteresis 11b = 20 °C hysteresis
0	LOCK_EN	RW	0b	Register lock protection enable/disable bit 0b = The register protection is disabled 1b = The register protection is enabled. When set the bit cannot be cleared by writing to the register to unlock the register protection. The feature when enabled, prevents application write to the temperature offset, temperature alert low, temperature alert high, stackmode address and device configuration registers.

7.6.6 Stackmode Address Register (Scratchpad-1 offset = 06h) [reset = 00h]

The register is used to program the stackmode address for the device. The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Table 7-12. Stackmode Address Register

7	6	5	4	3	2	1	0
STACKMODE_ADDRESS[7:0]							

Table 7-12. Stackmode Address Register (continued)

7	6	5	4	3	2	1	0
RW-00h							

Table 7-13. Stackmode Address Register Field Descriptions

Bit	Field	Type	Reset	Description
7:0	STACKMODE_ADDRESS[7:0]	RW	00h	Stores the stackmode address for the device when stacked conversion mode is used to stagger the temperature conversions.

7.6.7 Temperature Alert Low LSB Register (Scratchpad-1 offset = 08h) [reset = 00h]

This register provides the LSB for the low temperature alert threshold to compare with the latest temperature conversion result. The register on the first power up has the alert threshold set in legacy format. If there is a change of format, then the application must update the register in the new format. If the latest temperature conversion result is less than the threshold set, then the device shall update the alert low status flag in the status register, respond with the status bit flagged for an alert during the ALERTSEARCH command, and set the alert pin low if the device is in V_{DD} powered mode.

The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Figure 7-32. Temperature Alert Low Register

7	6	5	4	3	2	1	0
ALERT_LOW[7:0]							
RW-00h							

Table 7-14. Temperature Alert Low Register Field Descriptions

Bit	Field	Type	Reset	Description
7:0	ALERT_LOW[7:0]	RW	00h	Stores the LSB of the alert low limit for comparison with the last temperature conversion result

7.6.8 Temperature Alert Low MSB Register (Scratchpad-1 offset = 09h) [reset = 00h]

This register provides the MSB for the low temperature alert threshold to compare with the latest temperature conversion result. The register on the first power up has the alert threshold set in legacy format. If there is a change of format, then the application must update the register in the new format. If the latest temperature conversion result is less than the threshold set, then the device shall update the alert low status flag in the status register, respond with the status bit flagged for an alert during the ALERTSEARCH command, and set the alert pin low if the device is in V_{DD} powered mode.

The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Table 7-15.

7	6	5	4	3	2	1	0
ALERT_LOW[15:8]							
RW-00h							

Table 7-16.

Bit	Field	Type	Reset	Description
7:0	ALERT_LOW[15:8]	RW	00h	Stores the MSB of the alert low limit for comparison with the last temperature conversion result

7.6.9 Temperature Alert High LSB Register (Scratchpad-1 offset = 0Ah) [reset = F0h]

This register provides the LSB for the high temperature alert threshold to compare with the latest temperature conversion result. The register on the first power up has the alert threshold set in legacy format. If there is a change of format, then the application must update the register in the new format. If the latest temperature conversion result is more than the threshold set, then the device shall update the alert high status flag in the status register, respond with the status bit flagged for an alert during the ALERTSEARCH command, and set the alert pin low if the device is in V_{DD} powered mode.

The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Figure 7-33. Temperature Alert High Register

7	6	5	4	3	2	1	0
ALERT_HIGH[7:0]							
RW-F0h							

Table 7-17. Temperature Alert High Register Field Descriptions

Bit	Field	Type	Reset	Description
7:0	ALERT_HIGH[7:0]	RW	F0h	Stores the LSB of the alert high limit for comparison with the last temperature conversion result

7.6.10 Temperature Alert High MSB Register (Scratchpad-1 offset = 0Bh) [reset = 07h]

This register provides the MSB for the high temperature alert threshold to compare with the latest temperature conversion result. The register on the first power up has the alert threshold set in legacy format. If there is a change of format, then the application must update the register in the new format. If the latest temperature conversion result is more than the threshold set, then the device shall update the alert high status flag in the status register, respond with the status bit flagged for an alert during the ALERTSEARCH command, and set the alert pin low if the device is in V_{DD} powered mode.

The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Figure 7-34. Temperature Alert High MSB Register

7	6	5	4	3	2	1	0
ALERT_HIGH[15:8]							
RW-07h							

Table 7-18. Temperature Alert High MSB Register Field Description

Bit	Field	Type	Reset	Description
7:0	ALERT_HIGH[15:8]	RW	07h	Stores the MSB of the alert high limit for comparison with the last temperature conversion result

7.6.11 Temperature Offset LSB Register (Scratchpad-1 offset = 0Ch) [reset = 00h]

The register is used to store the LSB of the offset calibration for the temperature sensor. The register on the first power up has the temperature offset set in legacy format. If there is a change of format, then the application must update the register in the new format. After every temperature conversion, the offset calibration is automatically applied to the temperature result, before being stored in the TEMP_RESULT_L and TEMP_RESULT_H registers.

The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Figure 7-35. Temperature Offset LSB Register

7	6	5	4	3	2	1	0
TEMP_OFFSET_L[7:0]							
RW-00h							

Table 7-19. Temperature Offset LSB Register Field Descriptions

Bit	Field	Type	Reset	Description
7:0	TEMP_OFFSET_L[7:0]	RW	00h	Stores the offset correction LSB for the temperature result

7.6.12 Temperature Offset MSB Register (Scratchpad-1 offset = 0Dh) [reset = 00h]

The register is used to store the MSB of the offset calibration for the temperature sensor. The register on the first power up has the temperature offset set in legacy format. If there is a change of format, then the application must update the register in the new format. After every temperature conversion, the offset calibration is automatically applied to the temperature result, before being stored in the TEMP_RESULT_L and TEMP_RESULT_H registers.

The host can store the updated setting to the configuration EEPROM using the COPY SCRATCHPAD-1 function command. At power-on reset, the register setting is automatically restored from the configuration EEPROM.

Return to [Register Map](#).

Figure 7-36. Temperature Offset MSB Register

7	6	5	4	3	2	1	0
TEMP_OFFSET_H[15:8]							
RW-00h							

Table 7-20. Temperature Offset MSB Register Field Descriptions

Bit	Field	Type	Reset	Description
7:0	TEMP_OFFSET_H[15:8]	RW	00h	Stores the offset correction MSB for the temperature result

7.6.13 IO Read Register [reset = F0h]

The register is used to read the state of the IO0 to IO3 pin. The register values are updated when the GPIO READ function is issued by the host or when the GPIO configuration is written using the GPIO WRITE function. When IO2 is configured to function as an alert pin, it provides a status of the alert pin.

Return to [Register Map](#).

Figure 7-37. IO Read Register

7	6	5	4	3	2	1	0
nIO3_STATE	nIO2_STATE	nIO1_STATE	nIO0_STATE	IO3_STATE	IO2_STATE	IO1_STATE	IO0_STATE
R-1b	R-1b	R-1b	R-1b	R-0b	R-0b	R-0b	R-0b

Table 7-21. IO Read Register Field Descriptions

Bit	Field	Type	Reset	Description
7	nIO3_STATE	R	1b	Read inverted value of the IO3 pin when configured as a digital input or output
6	nIO2_STATE	R	1b	Read inverted value of the IO2 pin when configured as a digital input or output
5	nIO1_STATE	R	1b	Read inverted value of the IO1 pin when configured as a digital input or output
4	nIO0_STATE	R	1b	Read inverted value of the IO0 pin when configured as a digital input or output
3	IO3_STATE	R	0b	Read value of the IO3 pin when configured as a digital input or output

Table 7-21. IO Read Register Field Descriptions (continued)

Bit	Field	Type	Reset	Description
2	IO2_STATE	R	0b	Read value of the IO2 pin when configured as a digital input or output
1	IO1_STATE	R	0b	Read value of the IO1 pin when configured as a digital input or output
0	IO0_STATE	R	0b	Read value of the IO0 pin when configured as a digital input or output

7.6.14 IO Configuration Register [reset = 00h]

The register is used to select the IO function for the pins marked IO0-IO3 on the device. When selected to function as a digital open-drain output, the pin shall be able to drive a 0 or 1 externally for controlling the gate or base of a transistor on IO0 to IO3 pin.

Return to [Register Map](#).

Figure 7-38. IO Configuration Register

7	6	5	4	3	2	1	0
IO3_SEL[1:0]		IO2_SEL[1:0]		IO1_SEL[1:0]		IO0_SEL[1:0]	
RW-00b		RW-00b		RW-00b		RW-00b	

Table 7-22. IO Configuration Register Field Descriptions

Bit	Field	Type	Reset	Description
7:6	IO3_SEL[1:0]	RW	00b	Selects the function of the IO 00b = IO3 is configured as input buffer and can be read 01b = Reserved 10b = IO3 is configured as an output in open drain mode and the IO is driven as '0' 11b = IO3 is configured as an output in open drain mode and the IO is driven as '1'
5:4	IO2_SEL[1:0]	RW	00b	Selects the function of the IO 00b = IO2 is configured as input buffer and can be read 01b = IO2 is configured as an open drain active low alert 10b = IO2 is configured as an output in open drain mode and the IO is driven as '0' 11b = IO2 is configured as an output in open drain mode and the IO is driven as '1'
3:2	IO1_SEL[1:0]	RW	00b	Selects the function of the IO 00b = IO1 is configured as input buffer and can be read 01b = Reserved 10b = IO1 is configured as an output in open drain mode and the IO is driven as '0' 11b = IO1 is configured as an output in open drain mode and the IO is driven as '1'
1:0	IO0_SEL[1:0]	RW	00b	Selects the function of the IO 00b = IO0 is configured as input buffer and can be read 01b = Reserved 10b = IO0 is configured as an output in open drain mode and the IO is driven as '0' 11b = IO0 is configured as an output in open drain mode and the IO is driven as '1'

8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

8.1 Application Information

The TMP1826 can operate as a single-wire half duplex bus, either in supply or bus powered mode. The TMP1826 features a thermal sensor with an integrated 2-Kbit user EEPROM for applications requiring identification with lesser number of components due to space constraints. The device also features an integrated CRC that may be used for ensuring data integrity during communication.

The bus powered mode is designed for applications working without a dedicated power supply pin and can reduce cabling costs. As the device current consumption during thermal conversion and EEPROM operations is low, the device may not require a low impedance current path, thereby reducing the need for additional FET or load switch and current limiting resistor to bypass the bus pullup resistor. The pullup resistor used during bus powered mode must be correctly sized to ensure that sufficient current can be supplied during a thermal conversion and EEPROM operation, and input pin voltage does not fall below the $V_{IH(MIN)}$.

Additionally, if the host needs to reset the device when operating in bus powered mode, the host must pull the communication line low for at least 100 ms. This allows the internal capacitor of the device to discharge and prepare the device for power on reset.

8.2 Typical Applications

8.2.1 Bus Powered Application

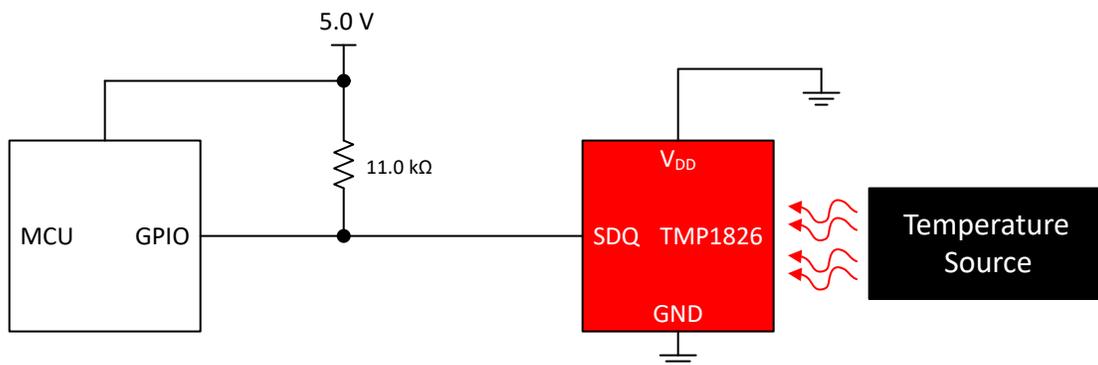


Figure 8-1. Bus Powered Application

8.2.1.1 Design Requirements

For this design example, use the parameters listed below:

Table 8-1. Design Parameters

Parameter	Value
Power mode	Bus Powered
Supply (V_{DD})	5.0 V
Pullup resistor (R_{PUR})	11.0 kΩ

8.2.1.2 Detailed Design Procedure

To reduce the wire count, the bus powered mode for TMP1826 is the primary mode of operation. The V_{DD} pin of the device must be connected to GND and the SDQ pin of the device must be connected to the host GPIO with a pullup resistor.

To calculate the maximum value of the pullup resistor, substitute the value for V_{PUR} and $I_{PU(MIN)}$ in Equation 1.

$$R_{PUR} < (5.0 \text{ V} - 1.6 \text{ V}) \div 300 \mu\text{A}$$

$$R_{PUR} < 11.333 \text{ k}\Omega$$

The actual value of the pull-up resistor can then be adjusted based on the speed of communication and bus or cable parasitic capacitance.

When the V_{DD} is activated, the TMP1826 draws current through the pullup resistor to charge its internal capacitors. When the internal capacitor is charged to the pullup voltage, the host can start communication. The bus idle state is high, which is maintained by the pullup resistor, when the host puts its GPIO in high impedance state.

The TMP1826 uses the stored charge to operate when the SDQ pin is low and measures the low period to decode bus reset, logic high and logic low sent by the host. Similarly, when the host reads data from the TMP1826, it changes the state of the bus from high to low and releases the bus. Depending on whether the device has to send a logic low or logic high, the device shall either hold the bus low or release the bus immediately.

8.2.2 Supply Powered Application

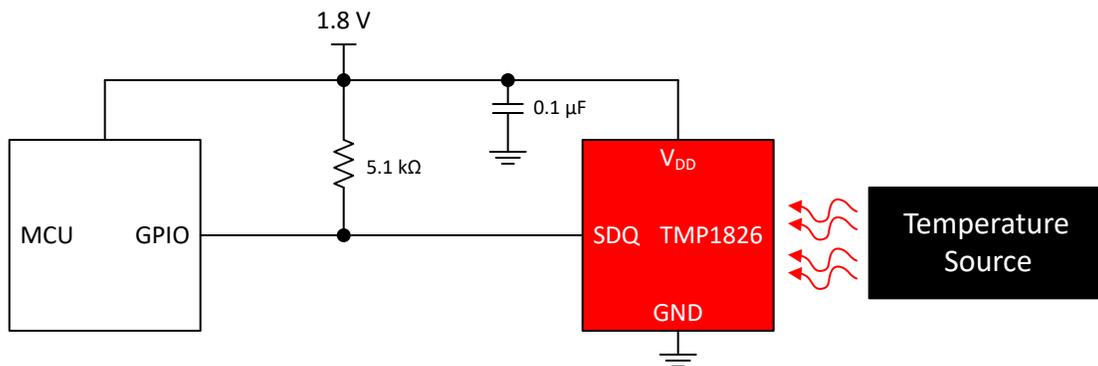


Figure 8-2. Supply Powered Application

8.2.2.1 Design Requirements

For this design example, use the parameters listed below:

Table 8-2. Design Parameters

Parameters	
Power mode	V_{DD} Powered
Supply (V_{DD})	1.8 V
Pullup resistor (R_{PUR})	5.1 k Ω

8.2.2.2 Detailed Design Procedure

The supply powered mode uses the V_{DD} pin connected to the same supply rail as the host and pullup resistor. TI recommends to put a 0.1- μF bypass capacitor close to the V_{DD} pin of the TMP1826.

The pullup resistor value of 5.1 k Ω , is large enough to provide proper communication with standard speed and avoid V_{OL} violation when the device is sending data to the host. The user may change the value based on the total bus load and application operating requirements.

The communication protocol for supply powered mode is same as that for bus powered mode, which allows the entire software stack to be reused. This mode of operation is useful for onboard thermal sensing applications as it provides for continuous conversion and alert function.

8.2.3 UART Interface for Communication

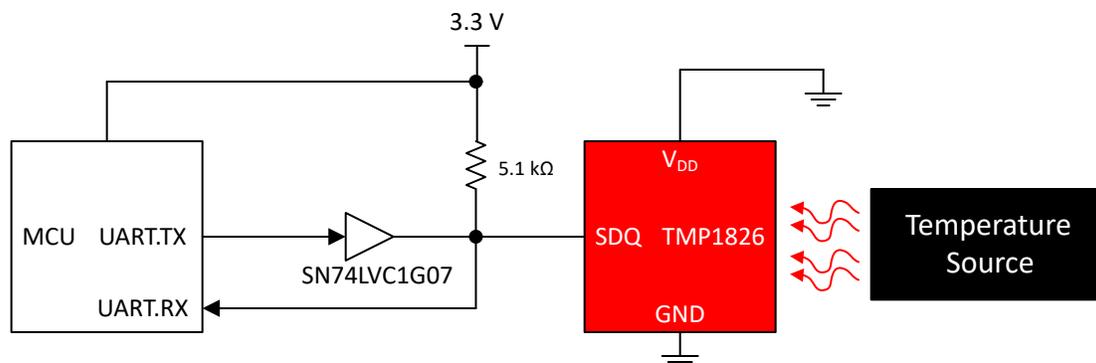


Figure 8-3. Using UART to interface TMP1826

8.2.3.1 Design Requirements

For this design example, use the parameters listed below:

Table 8-3. Design Parameters

Parameter	Value
Power Mode	Bus powered
Supply (V_{DD})	3.3 V
Pullup resistor (R_{PUR})	5.1 kΩ

8.2.3.2 Detailed Design Procedure

If using GPIO for communication is not possible due to any reason, it is also possible to use UART peripheral that is available on most host controllers to interface with the TMP1826. UART is a push-pull full duplex bus and to interface with TMP1826, it requires a buffer with open-drain driver like the [SN74LVC1G07](#).

The input of the buffer is connected to the UART transmit pin and the output of the buffer is connected to the SDQ pin on the TMP1826. The output of the buffer is also connected to the UART receive pin on the host. As the output is open-drain, it requires a pullup resistor which can be calculated using [Equation 1](#). Substituting the value for $V_{PUR} = 3.3 \text{ V}$ and $I_{PU(MIN)} = 300 \mu\text{A}$, the R_{PUR} value selected must be less than 5.67 kΩ.

In software, the application must adjust its baud rate so that it can send bus reset to the device by sending 00h. The start bit of the UART frame which is always 0, provides the required falling edge for data sent to the TMP1826. When sending a logic high to the device, the UART shall send FFh to the TMP1826 and, when sending a logic low to the device, the UART shall send C0h. As UART is a full duplex bus, the host must flush its receive buffers during a transmit operation.

When receiving data from the TMP1826, the host shall send FFh and the device when transmitting a logic high will detect and release the bus, while when transmitting a logic low will detect and hold the bus. As a result, the host shall receive a FFh for a logic high and F0h for a logic low depending on the baud rate configured.

9 Power Supply Recommendations

The TMP1826 operates with a power supply in the range of 1.7 V to 5.5 V in both V_{DD} powered and bus powered modes. When operating in V_{DD} powered mode, a power-supply bypass capacitor is required for precision and stability. Place this power-supply bypass capacitor as close to the supply and ground pins of the device as possible. A typical value for this supply bypass capacitor is 0.1 μ F. Applications with noisy or high-impedance power supplies can require a bigger bypass capacitor to reject power-supply noise.

In bus powered mode, the V_{DD} pin must be connected to ground. The internal capacitor in the device is sufficient to provide power during bus communication. The internal capacitor is recharged through the external pullup resistor during the recovery period. In cases, where there is a long bus length or at higher temperatures, it may be necessary for the host to provide additional time for bus recovery or to use the overdrive speed in which the part uses the internal capacitor charge less.

When using IO pins to control external circuits, take care that currents to these pins do not heat the part and offset temperature measurements.

10 Layout

10.1 Layout Guidelines

Place the power-supply bypass capacitor as close as possible to the supply and ground pins when in supply powered mode. The recommended value of the capacitor is 0.1 μ F. The open-drain SDQ pin requires an external pullup resistor which must not be higher than R_{PUR} .

When in bus powered mode, only the external pullup resistor is required for the open-drain SDQ pin.

To achieve a high precision temperature reading for a rigid PCB, do not solder the thermal pad. For a flexible PCB, the user may solder the thermal pad to the increase board level reliability. If the thermal pad is soldered, then it should be connected to the ground.

10.2 Layout Example

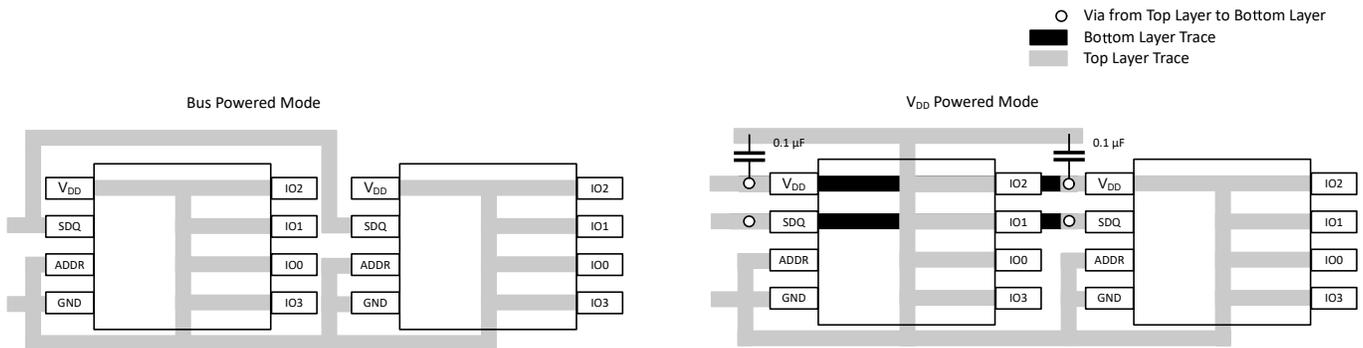


Figure 10-1. Layout Example

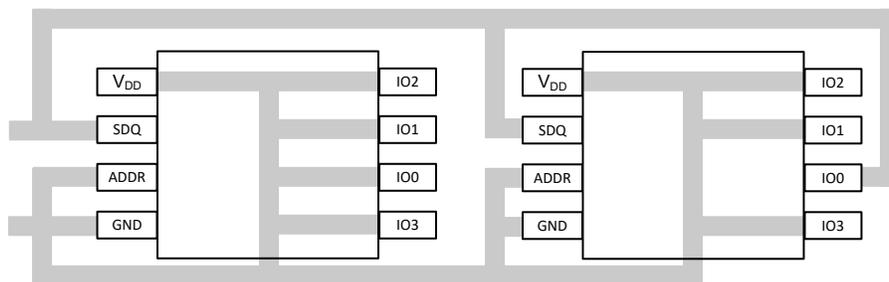


Figure 10-2. IO Hardware Address in Bus Powered Mode

11 Device and Documentation Support

11.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Subscribe to updates* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

11.2 Support Resources

[TI E2E™ support forums](#) are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

11.5 Glossary

[TI Glossary](#) This glossary lists and explains terms, acronyms, and definitions.

12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
PTMP1826DGKT	ACTIVE	VSSOP	DGK	8	250	TBD	Call TI	Call TI	-40 to 125		Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "-" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

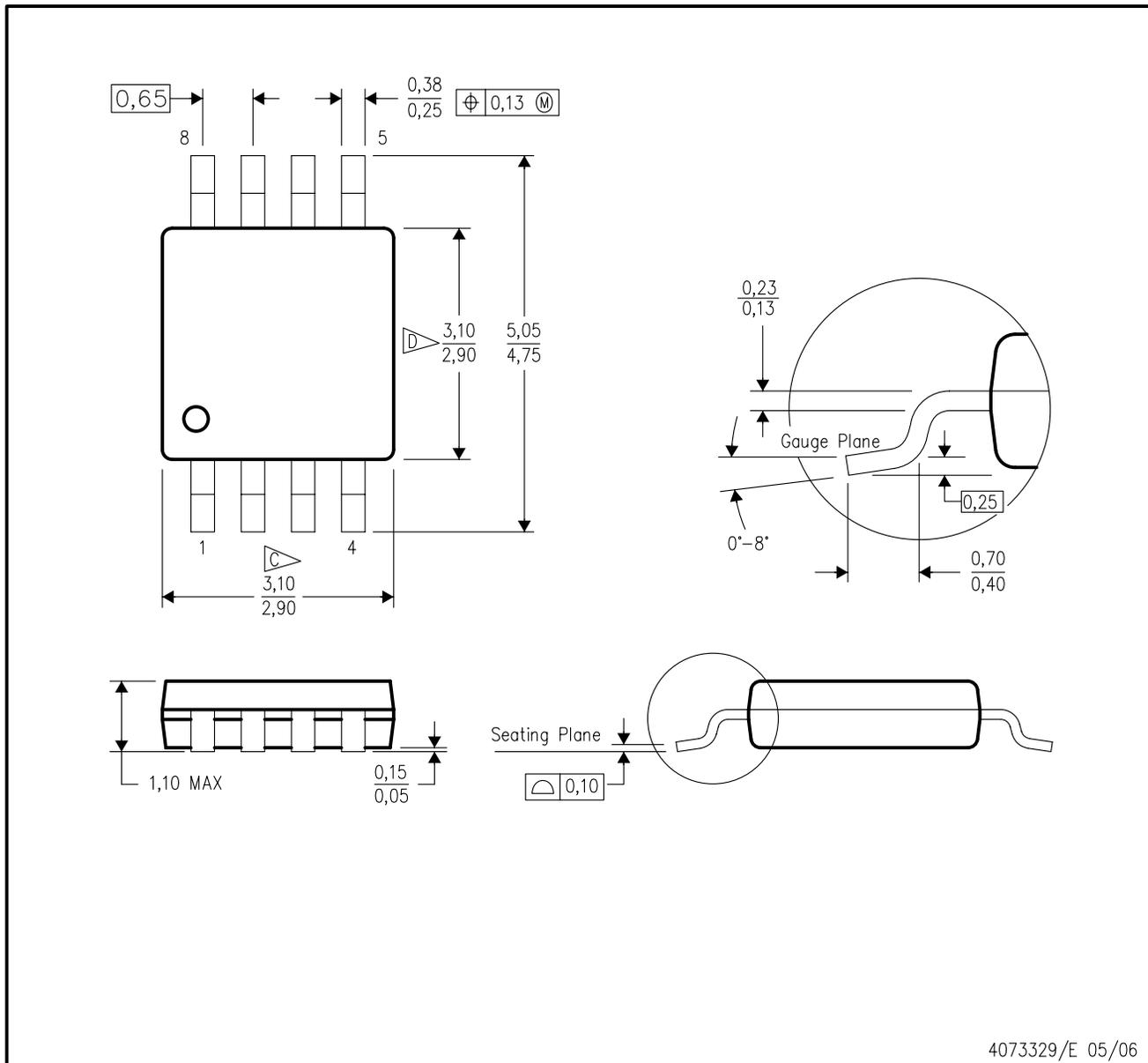
(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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DGK (S-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
 - D. Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
 - E. Falls within JEDEC MO-187 variation AA, except interlead flash.

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